PCTEST ENGINEERING LABORATORY, INC.
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http://www.pctestlab.com

MEASUREMENT REPORT
FCC Part 22, 24, & 27 LTE

Applicant Name:
Samsung Electronics, Co. Ltd.
129, Samsung-ro, Maetan dong,
Yeongtong-gu, Suwon-si
Gyeonggi-do 443-742, Korea

Date of Testing:
5/22 - 6/10/2014
Test Site/Location:
PCTEST Lab., Columbia, MD, USA
Test Report Serial No.:
0Y1405221058.A3L

FCC ID : A3LSMG860P

APPLICANT: SAMSUNG ELECTRONICS, CO. LTD.

FCC Classification: PCS Licensed Transmitter Held to Ear (PCE)
FCC Rule Part(s): §2; §22; §24; §27
Test Procedure(s): ANSI/TIA-603-C-2004, KDB 971168 v02r01
EUT Type: Portable Handset
Model(s): SM-G860P
Test Device Serial No.: *identical prototype* [S/N: SP1D7290341K]

Mode	Tx Frequency (MHz)	Emission Designator	Modulation	ERP/EIRP	
				Max. Power (W)	Max. Power (dBm)
LTE Band 26	824.7 - 848.3	1M12G7D	QPSK	0.094	19.74
LTE Band 26	824.7 - 848.3	1M12W7D	16QAM	0.073	18.65
LTE Band 26	825.5 - 847.5	2M72G7D	QPSK	0.106	20.26
LTE Band 26	825.5 - 847.5	2M70W7D	16QAM	0.083	19.18
LTE Band 26	826.5 - 846.5	4M49G7D	QPSK	0.095	19.76
LTE Band 26	826.5 - 846.5	4M49W7D	16QAM	0.077	18.84
LTE Band 26	829 - 844	8M99G7D	QPSK	0.075	18.75
LTE Band 26	829 - 844	8M98W7D	16QAM	0.058	17.63
LTE Band 25	1850.7 - 1914.3	1M12G7D	QPSK	0.242	23.83
LTE Band 25	1850.7 - 1914.3	1M12W7D	16QAM	0.185	22.66
LTE Band 25	1851.5 - 1913.5	2M72G7D	QPSK	0.214	23.30
LTE Band 25	1851.5 - 1913.5	2M72W7D	16QAM	0.157	21.96
LTE Band 25	1852.5 - 1912.5	4M50G7D	QPSK	0.216	23.35
LTE Band 25	1852.5 - 1912.5	4M51W7D	16QAM	0.163	22.11
LTE Band 25	1855 - 1910	8M98G7D	QPSK	0.198	22.96
LTE Band 25	1855 - 1910	8M95W7D	16QAM	0.150	21.77
LTE Band 25	1857.5 - 1907.5	13M4G7D	QPSK	0.115	20.60
LTE Band 25	1857.5 - 1907.5	13M5W7D	16QAM	0.092	19.63
LTE Band 25	1860 - 1905	17M9G7D	QPSK	0.126	21.00
LTE Band 25	1860 - 1905	17M9W7D	16QAM	0.097	19.88
LTE Band 41	2499 - 2687	4M49G7D	QPSK	0.358	25.54
LTE Band 41	2499 - 2687	4M49W7D	16QAM	0.295	24.70
LTE Band 41	2502 - 2685	8M98G7D	QPSK	0.337	25.28
LTE Band 41	2502 - 2685	8M94W7D	16QAM	0.258	24.11
LTE Band 41	2505 - 2682	13M4G7D	QPSK	0.323	25.09
LTE Band 41	2505 - 2682	13M5W7D	16QAM	0.229	23.59
LTE Band 41	2508 - 2679	17M9G7D	QPSK	0.352	25.46
LTE Band 41	2508 - 2679	17M9W7D	16QAM	0.229	23.59

This equipment has been shown to be capable of compliance with the applicable technical standards as indicated in the measurement report and was tested in accordance with the measurement procedures specified in §2.947. Test results reported herein relate only to the item(s) tested.

I attest to the accuracy of data. All measurements reported herein were performed by me or were made under my supervision and are correct to the best of my knowledge and belief. I assume full responsibility for the completeness of these measurements and vouch for the qualifications of all persons taking them.

Randy Ortanez
President

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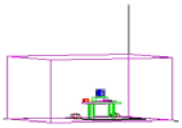
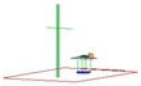


MEASUREMENT REPORT
FCC Part 22, 24, & 27

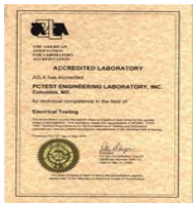


§2.1033 General Information

APPLICANT:	Samsung Electronics, Co. Ltd.
APPLICANT ADDRESS:	129, Samsung-ro, Maetan dong, Yeongtong-gu, Suwon-si, Gyeonggi-do 443-742, Korea
TEST SITE:	PCTEST ENGINEERING LABORATORY, INC.
TEST SITE ADDRESS:	7185 Oakland Mills Road, Columbia, MD 21045 USA
FCC RULE PART(S):	§2; §22; §24; §27
BASE MODEL:	SM-G860P
FCC ID:	A3LSMG860P
FCC CLASSIFICATION:	PCS Licensed Transmitter Held to Ear (PCE)
FREQUENCY TOLERANCE:	±0.00025 % (2.5 ppm)
Test Device Serial No.:	SP1D7290341K ☐ Production ☒ Pre-Production ☐ Engineering
DATE(S) OF TEST:	5/22 - 6/10/2014
TEST REPORT S/N:	0Y1405221058.A3L

Test Facility / Accreditations

Measurements were performed at PCTEST Engineering Lab located in Columbia, MD 21046, U.S.A.



- PCTEST facility is an FCC registered (PCTEST Reg. No. 159966) test facility with the site description report on file and has met all the requirements specified in Section 2.948 of the FCC Rules and Industry Canada (2451B-1).
- PCTEST Lab is accredited to ISO 17025 by U.S. National Institute of Standards and Technology (NIST) under the National Voluntary Laboratory Accreditation Program (NVLAP Lab code: 100431-0) in EMC, FCC and Telecommunications.
- PCTEST Lab is accredited to ISO 17025-2005 by the American Association for Laboratory Accreditation (A2LA) in Specific Absorption Rate (SAR) testing, Hearing Aid Compatibility (HAC) testing, CTIA Test Plans, and wireless testing for FCC and Industry Canada Rules.
- PCTEST Lab is a recognized U.S. Conformity Assessment Body (CAB) in EMC and R&TTE (n.b. 0982) under the U.S.-EU Mutual Recognition Agreement (MRA).
- PCTEST TCB is a Telecommunication Certification Body (TCB) accredited to ISO/IEC Guide 65 by the American National Standards Institute (ANSI) in all scopes of FCC Rules and Industry Canada Standards (RSS).
- PCTEST facility is an IC registered (2451B-1) test laboratory with the site description on file at Industry Canada.
- PCTEST is a CTIA Authorized Test Laboratory (CATL) for AMPS, CDMA, and EvDO wireless devices and for Over-the-Air (OTA) Antenna Performance testing for AMPS, CDMA, GSM, GPRS, EGPRS, UMTS (W-CDMA), CDMA 1xEVDO, and CDMA 1xRTT.

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1.0 INTRODUCTION

1.1 Scope

Measurement and determination of electromagnetic emissions (EME) of radio frequency devices including intentional and/or unintentional radiators for compliance with the technical rules and regulations of the Federal Communications Commission and the Industry Canada Certification and Engineering Bureau.

1.2 Testing Facility

The map below shows the location of the PCTEST LABORATORY, its proximity to the FCC Laboratory, the Columbia vicinity, the Baltimore-Washington Internt'l (BWI) airport, the city of Baltimore and the Washington, DC area. (S*ee Figure 1-1*).

These measurement tests were conducted at the PCTEST Engineering Laboratory, Inc. facility located at 7185 Oakland Mills Road, Columbia, MD 21046. The site coordinates are 39° 10'23" N latitude and 76° 49'50" W longitude. The facility is 0.4 miles North of the FCC laboratory, and the ambient signal and ambient signal strength are approximately equal to those of the FCC laboratory. The detailed description of the measurement facility was found to be in compliance with the requirements of § 2.948 according to ANSI C63.4-2003 on February 15, 2012.

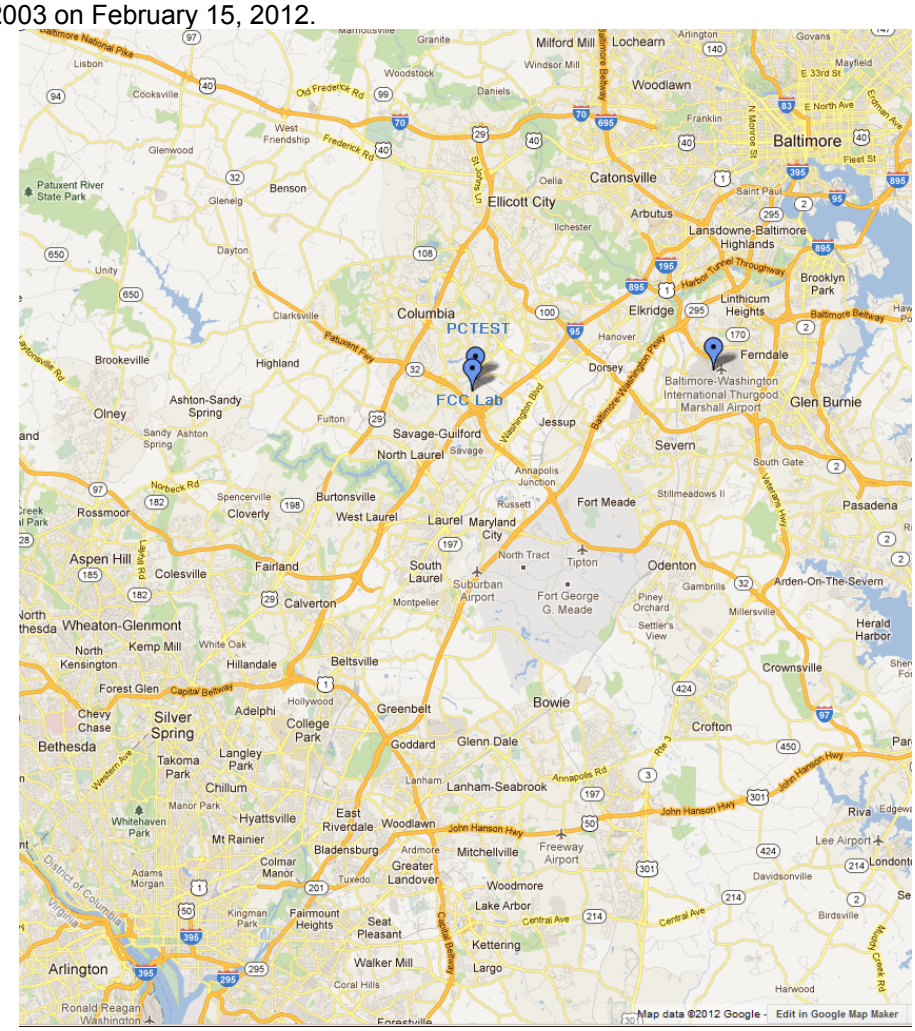

Figure 1-1. Map of the Greater Baltimore and Metropolitan Washington, D.C. area

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2.0 PRODUCT INFORMATION

2.1 Equipment Description

The Equipment Under Test (EUT) is the **Samsung Portable Handset FCC ID: A3LSMG860P**. The test data contained in this report pertains only to the emissions due to the EUT's LTE function.

2.2 Device Capabilities

This device contains the following capabilities:

850/1900 CDMA (BC0, BC1, BC10), 850/1900 GPRS/EDGE, 850/1900 WCDMA/HSPA, Multi-Band LTE, 802.11a/b/g/n/ac WLAN, 802.11a/n/ac UNII, Bluetooth (1x, EDR, LE), NFC, ANT+

2.3 EMI Suppression Device(s)/Modifications

No EMI suppression device(s) were added and no modifications were made during testing.

2.4 Labeling Requirements

Per 2.925

The FCC identifier shall be permanently affixed to the equipment and shall be readily visible to the purchaser at the time of purchase.

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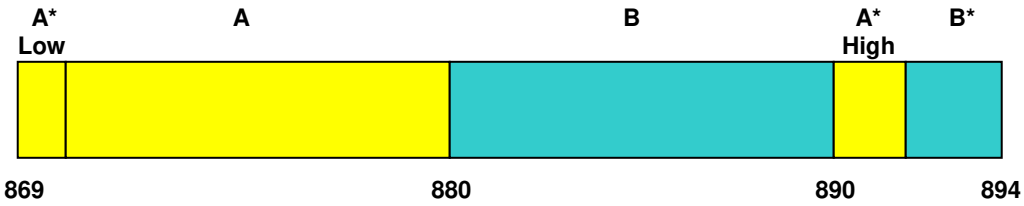
3.0 DESCRIPTION OF TESTS

3.1 Measurement Procedure

The measurement procedures described in the document titled "Land Mobile FM or PM – Communications Equipment – Measurements and Performance Standards" (ANSI/TIA-603-C-2004) and "Procedures for Compliance Measurement of the Fundamental Emission Power of Licensed Wideband (> 1 MHz) Digital Transmission Systems" (KDB 971168) were used in the measurement of the **Samsung Portable Handset FCC ID: A3LSMG860P.**

3.2 Cellular - Base Frequency Blocks

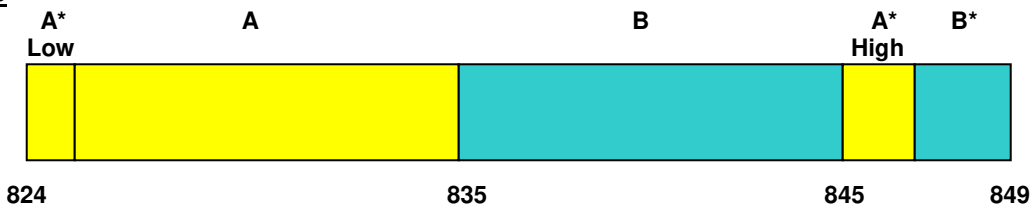
§22.905



BLOCK 1: 869 – 880 MHz (A* Low + A)
BLOCK 2: 880 – 890 MHz (B)
BLOCK 3: 890 – 891.5 MHz (A* High)
BLOCK 4: 891.5 – 894 MHz (B*)

3.3 Cellular - Mobile Frequency Blocks

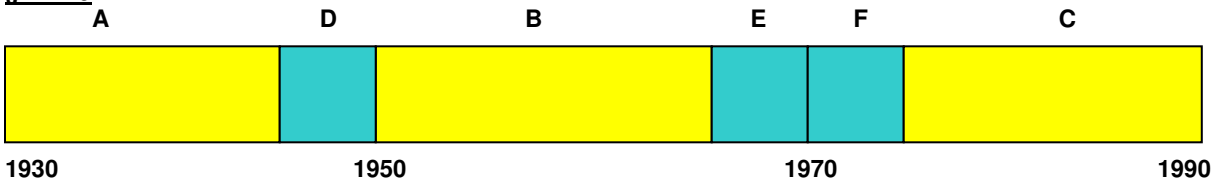
§22.905



BLOCK 1: 824 – 835 MHz (A* Low + A)
BLOCK 2: 835 – 845 MHz (B)
BLOCK 3: 845 – 846.5 MHz (A* High)
BLOCK 4: 846.5 – 849 MHz (B*)

3.4 PCS - Base Frequency Blocks

§24.229



BLOCK 1: 1930 – 1945 MHz (A)
BLOCK 2: 1945 – 1950 MHz (D)
BLOCK 3: 1950 – 1965 MHz (B)
BLOCK 4: 1965 – 1970 MHz (E)
BLOCK 5: 1970 – 1975 MHz (F)
BLOCK 6: 1975 – 1990 MHz (C)

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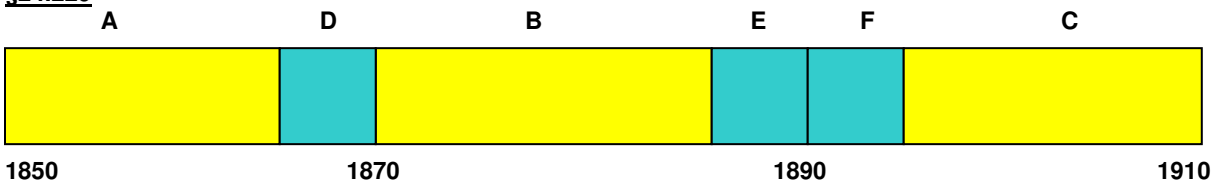
3.5 PCS - Mobile Frequency Blocks

§24.229



BLOCK 1: 1850 – 1865 MHz (A)
BLOCK 2: 1865 – 1870 MHz (D)
BLOCK 3: 1870 – 1885 MHz (B)
BLOCK 4: 1885 – 1890 MHz (E)
BLOCK 5: 1890 – 1895 MHz (F)
BLOCK 6: 1895 – 1910 MHz (C)

3.6 Radiated Power and Radiated Spurious Emissions

§2.1053 §22.913(a.2) §22.917(a) §24.232(c) §24.238(a)

The radiated test facilities consisted of an indoor 3 meter semi-anechoic chamber used for final measurements and exploratory measurements, when necessary. The measurement area is contained within the semi-anechoic chamber which is shielded from any ambient interference. The test site inside the chamber is a 6m x 5.2m elliptical, obstruction-free area in accordance with Clause 5, Figure 5.7 of ANSI C63.4-2009. For measurements above 1GHz absorbers are arranged on the floor between the turn table and the antenna mast in such a way so as to maximize the reduction of reflections. For measurements below 1GHz, the absorbers are removed. An ETS Lindgren Model 2188 raised turntable is used for radiated measurement. It is a continuously rotatable, remote-controlled, metallic turntable and 2 meters (6.56 ft.) in diameter. The turn table is flush with the raised floor of the chamber in order to maintain its function as a ground plane. A 78cm high PVC support structure is placed on top of the turntable. A ¾" (~1.9cm) sheet of high density polyethylene is used as the table top and is placed on top of the PVC supports to bring the total height of the table to 80cm.

The equipment under test was transmitting while connected to its integral antenna and is placed on a wooden turntable 80cm above the ground plane and 3 meters from the receive antenna. The receive antenna height is adjusted between 1 and 4 meter height, the turntable is rotated through 360 degrees, and the EUT is manipulated through all orthogonal planes representative of its typical use to achieve the highest reading on the receive spectrum analyzer. Radiated power levels are also investigated with the receive antenna horizontally and vertically polarized. The maximized power level is recorded using the spectrum analyzer "Channel Power" function with the integration band set to the emissions' occupied bandwidth, a RMS detector, RBW = 100kHz, VBW = 300kHz, and a 1 second sweep time over a minimum of 10 sweeps, per the guidelines of KDB 971168.

Per the guidance of ANSI/TIA-603-C-2004, a half-wave dipole is then substituted in place of the EUT. For emissions above 1GHz, a horn antenna is substituted in place of the EUT. The substitute antenna is driven by a signal generator with the level of the signal generator being adjusted to obtain the same receive spectrum analyzer level previously recorded from the spurious emission from the EUT. The power of the emission is calculated using the following formula:

$$P_{d\,[dBm]} = P_{g\,[dBm]} - \text{cable loss}_{\,[dB]} + \text{antenna gain}_{\,[dBd/dBi]}$$

Where, P_d is the dipole equivalent power, P_g is the generator output into the substitution antenna, and the antenna gain is the gain of the substitute antenna used relative to either a half-wave dipole (dBd) or an isotropic source (dBi). The substitute level is equal to $P_{g\,[dBm]}$ – cable loss $_{[dB]}$.

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The calculated P_d levels are then compared to the absolute spurious emission limit of -13dBm which is equivalent to the required minimum attenuation of 43 + $10\log_{10}$(Power $_{[Watts]}$). For Band 41, the calculated P_d levels are compared to the absolute spurious emission limit of -25dBm which is equivalent to the required minimum attenuation of 55 + $10\log_{10}$(Power $_{[Watts]}$).

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4.0 TEST EQUIPMENT CALIBRATION DATA

Test Equipment Calibration is traceable to the National Institute of Standards and Technology (NIST).

Manufacturer	Model	Description	Cal Date	Cal Interval	Cal Due	Serial Number
-	RE1	Radiated Emissions Cable Set (UHF/EHF)	3/25/2014	Annual	3/25/2015	N/A
-	LTx3	LIcensed Transmitter Cable Set	1/30/2014	Annual	1/30/2015	N/A
Agilent	8447D	Broadband Amplifier	5/30/2014	Annual	5/30/2015	2443A01900
Agilent	E4448A	PSA (3Hz-50GHz) Spectrum Analyzer	4/16/2014	Annual	4/16/2015	US42510244
Agilent	N9030A	PXA Signal Analyzer (44GHz)	1/17/2014	Annual	1/17/2015	MY52350166
Emco	6502	Active Loop Antenna (10k - 30 MHz)	5/31/2012	Biennial	5/31/2014	267
Espec	ESX-2CA	Environmental Chamber	4/16/2014	Annual	4/16/2015	17620
ETS Lindgren	3117	1-18 GHz DRG Horn (Medium)	4/8/2014	Biennial	4/8/2016	125518
ETS Lindgren	3164-08	Quad Ridge Horn Antenna	3/12/2014	Biennial	3/12/2016	128337
K & L	13SH10-1000/U1000	N Type High Pass Filter	5/22/2014	Annual	5/22/2015	1
K & L	11SH10-3075/U18000	High Pass Filter	5/2/2014	Annual	5/2/2015	4
Mini-Circuits	SSG-4000HP	USB Synthesized Signal Generator	N/A			11208010032
Mini-Circuits	SSG-4000HP	USB Synthesized Signal Generator	N/A			11208010032
Mini-Circuits	PWR-SENS-4RMS	USB Power Sensor	4/9/2014	Annual	4/9/2015	11401010036
Rohde & Schwarz	CMW500	LTE Radio Communication Tester	10/4/2013	Biennial	10/4/2015	103962
Rohde & Schwarz	TS-PR18	1-18 GHz Pre-Amplifier	3/5/2014	Annual	3/5/2015	100071
Rohde & Schwarz	ESU26	EMI Test Receiver (26.5GHz)	1/27/2014	Annual	1/27/2015	100342
Schwarzbeck	UHA 9105	Dipole Antenna (400 - 1GHz) Rx	11/21/2013	Biennial	11/21/2015	9105-2404
Seekonk	NC-100	Torque Wrench (8" lb)	4/16/2014	Annual	4/16/2015	N/A
Sunol	JB5	Bi-Log Antenna (30M - 5GHz)	1/28/2014	Biennial	1/28/2016	A051107

Table 4-1. Test Equipment

Notes:

1. For equipment listed above that has a calibration due date that falls within the test date range, care was taken to ensure that this equipment was utilized prior to the calibration due date.

2. Equipment with a calibration date of “N/A” shown in this list was not used to make direct calibrated measurements.

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5.0 SAMPLE CALCULATIONS

Emission Designator

QPSK Modulation

Emission Designator = 8M62G7D

LTE BW = 8.62 MHz
G = Phase Modulation
7 = Quantized/Digital Info
D = Amplitude/Angle Modulated

16QAM Modulation

Emission Designator = 8M45W7D

LTE BW = 8.45 MHz
W = Amplitude/Angle Modulated
7 = Quantized/Digital Info
D = Combination (Audio/Data)

Spurious Radiated Emission – LTE Band

Example: Middle Channel LTE Mode 2nd Harmonic (1564 MHz)

The average spectrum analyzer reading at 3 meters with the EUT on the turntable was –81.0 dBm. The gain of the substituted antenna is 8.1 dBi. The signal generator connected to the substituted antenna terminals is adjusted to produce a reading of –81.0 dBm on the spectrum analzyer. The loss of the cable between the signal generator and the terminals of the substituted antenna is 2.0 dB at 1564 MHz. So 6.1 dB is added to the signal generator reading of –30.9 dBm yielding –24.80 dBm. The fundamental EIRP was 25.501 dBm so this harmonic was 25.501 dBm – (-24.80).

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6.0 TEST RESULTS

6.1 Summary

Company Name: Samsung Electronics, Co. Ltd.
FCC ID: A3LSMG860P
FCC Classification: PCS Licensed Transmitter Held to Ear (PCE)
Mode(s): LTE

FCC Part Section(s)	Test Description	Test Limit	Test Condition	Result	Reference
TRANSMITTER MODE (TX)					
2.1049	Occupied Bandwidth	N/A	CONDUCTED	PASS	Section 6.2
2.1051 22.917(a) 24.238(a)	Band Edge / Conducted Spurious Emissions	> 43 + 10log$_{10}$ (P[Watts]) at Band Edge and for all out-of-band emissions		PASS	Section 6.3, 6.4
27.53(l)	Band Edge / Conducted Spurious Emissions	> 43 + 10log$_{10}$ (P[Watts]) at channel edges and > 55 + 10log$_{10}$ (P[Watts]) at 5.5MHz away and beyond channel edges		PASS	Section 6.3, 6.4
24.232(d)	Peak-Average Ratio	< 13 dB		PASS	Section 6.5
2.1046	Transmitter Conducted Output Power	N/A		PASS	See RF Exposure Report
2.1055. 22.355 24.235 27.54	Frequency Stability	< 2.5 ppm (Part 22) and fundamental emissions stay within authorized frequency block (Part 24, 27)		PASS	Section 6.8
22.913(a.2)	Effective Radiated Power (Band 26)	< 7 Watts max. ERP	RADIATED	PASS	Section 6.6
24.232(c) 27.50(h.2)	Equivalent Isotropic Radiated Power (Band 25, 41)	< 2 Watts max. EIRP		PASS	Section 6.6
2.1053 22.917(a) 24.238(a)	Undesirable Emissions	> 43 + 10log$_{10}$ (P[Watts]) for all out-of-band emissions		PASS	Section 6.7
27.53(l)	Undesirable Emissions	> 43 + 10log$_{10}$ (P[Watts]) at channel edges and > 55 + 10log$_{10}$ (P[Watts]) at 5.5MHz away and beyond channel edges		PASS	Section 6.7

Table 6-1. Summary of Test Results

Notes:

1) All modes of operation and data rates were investigated. The test results shown in the following sections represent the worst case emissions.
2) The analyzer plots (Sections 6.2, 6.3, 6.4, 6.5) were all taken with a correction table loaded into the analyzer. The correction table was used to account for the losses of the cables, directional couplers, and attenuators used as part of the system to maintain a link between the call box and the EUT at all frequencies of interest.
3) All antenna port conducted emissions testing was performed on a test bench with the antenna port of the EUT connected to the spectrum analyzer through calibrated cables, attenuators, and couplers.
4) For conducted spurious emissions, automated test software was used to measure emissions and capture the corresponding plots necessary to show compliance. The measurement software utilized is PCTEST "LTE Automation", Version 2.1.

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6.2 Occupied Bandwidth

§2.1049

Test Overview

The occupied bandwidth, that is the frequency bandwidth such that, below its lower and above its upper frequency limits, the mean powers radiated are each equal to 0.5 percent of the total mean power radiated by a given emission shall be measured. All modes of operation were investigated and the worst case configuration results are reported in this section.

Test Procedure Used

KDB 971168 v02r01 – Section 4.2

Test Settings

1. The signal analyzer's automatic bandwidth measurement capability was used to perform the 99% occupied bandwidth and the 26dB bandwidth. The bandwidth measurement was not influenced by any intermediate power nulls in the fundamental emission.
2. RBW = 1 – 5% of the expected OBW
3. VBW ≥ 3 x RBW
4. Detector = Peak
5. Trace mode = max hold
6. Sweep = auto couple
7. The trace was allowed to stabilize
8. If necessary, steps 2 – 7 were repeated after changing the RBW such that it would be within 1 – 5% of the 99% occupied bandwidth observed in Step 7

Test Setup

The EUT and measurement equipment were set up as shown in the diagram below.

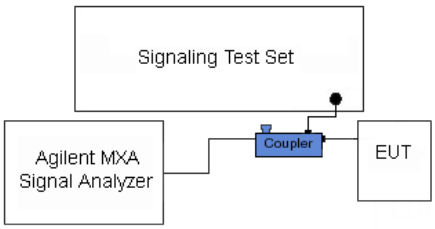

Figure 6-1. Test Instrument & Measurement Setup

Test Notes

None.

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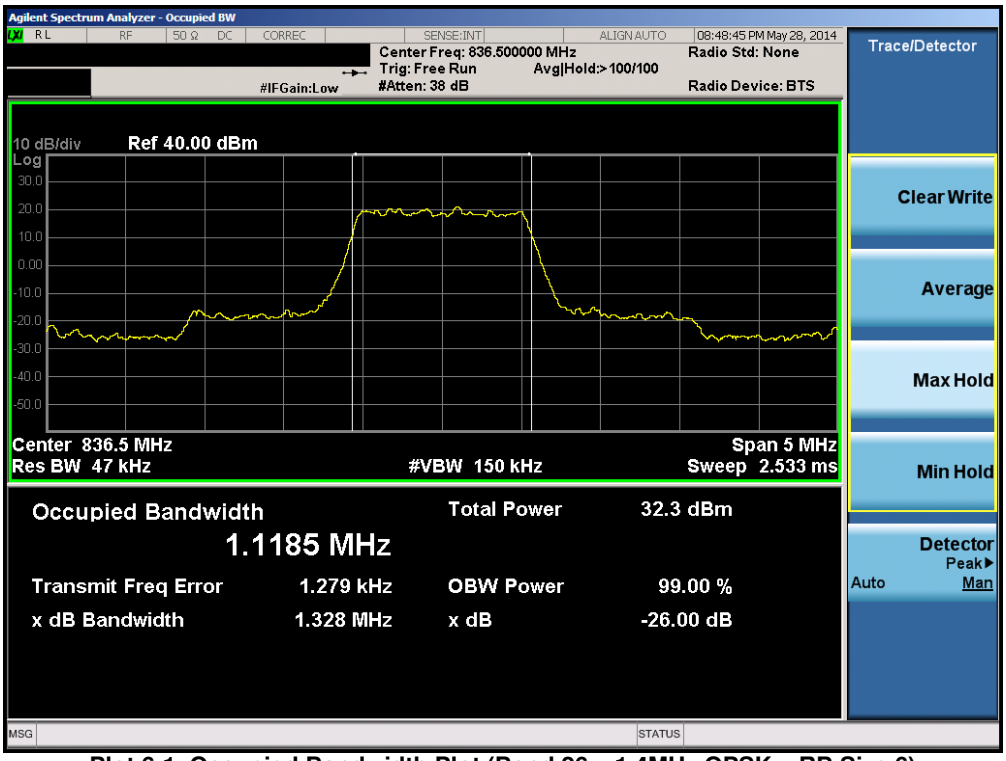
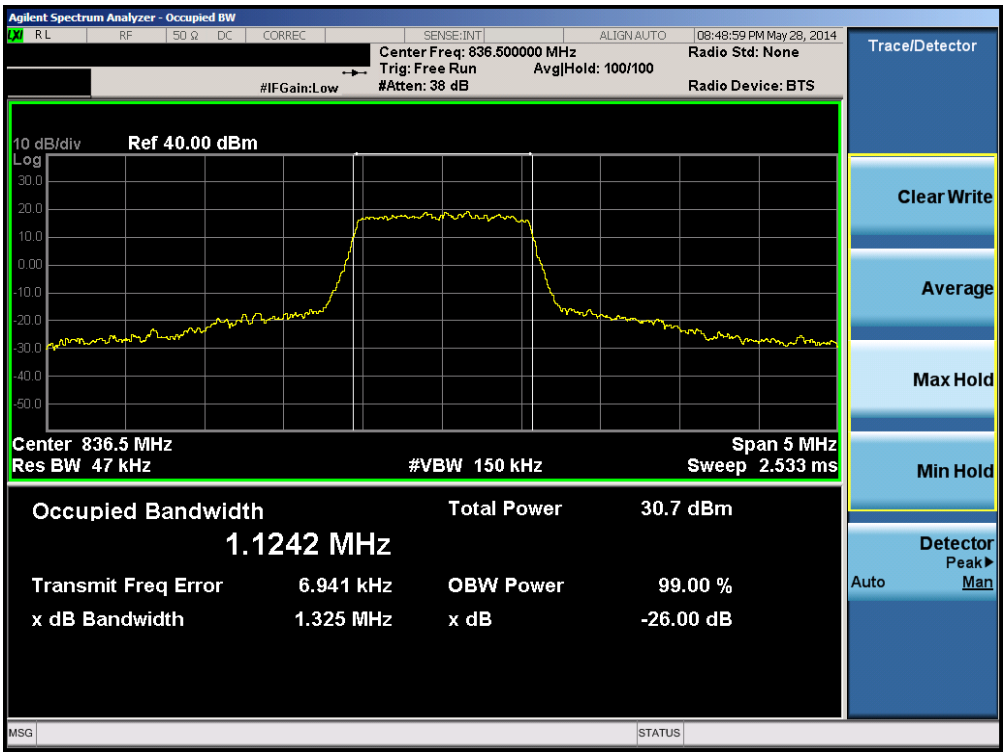


Plot 6-1. Occupied Bandwidth Plot (Band 26 – 1.4MHz QPSK – RB Size 6)



Plot 6-2. Occupied Bandwidth Plot (Band 26 – 1.4MHz 16-QAM – RB Size 6)

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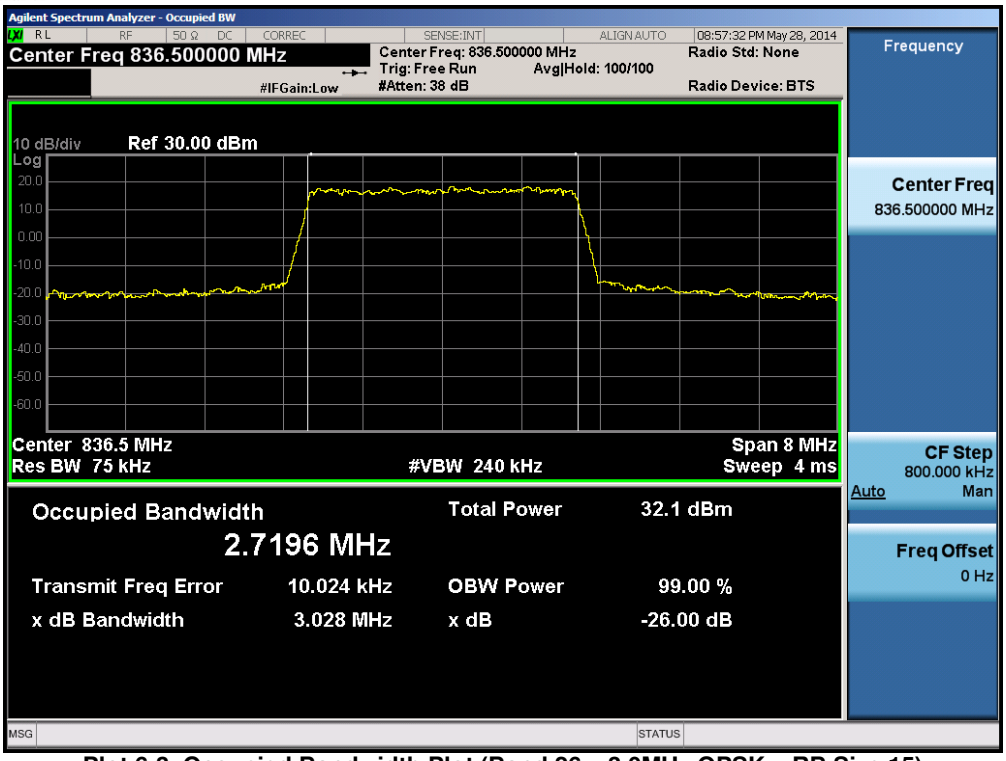
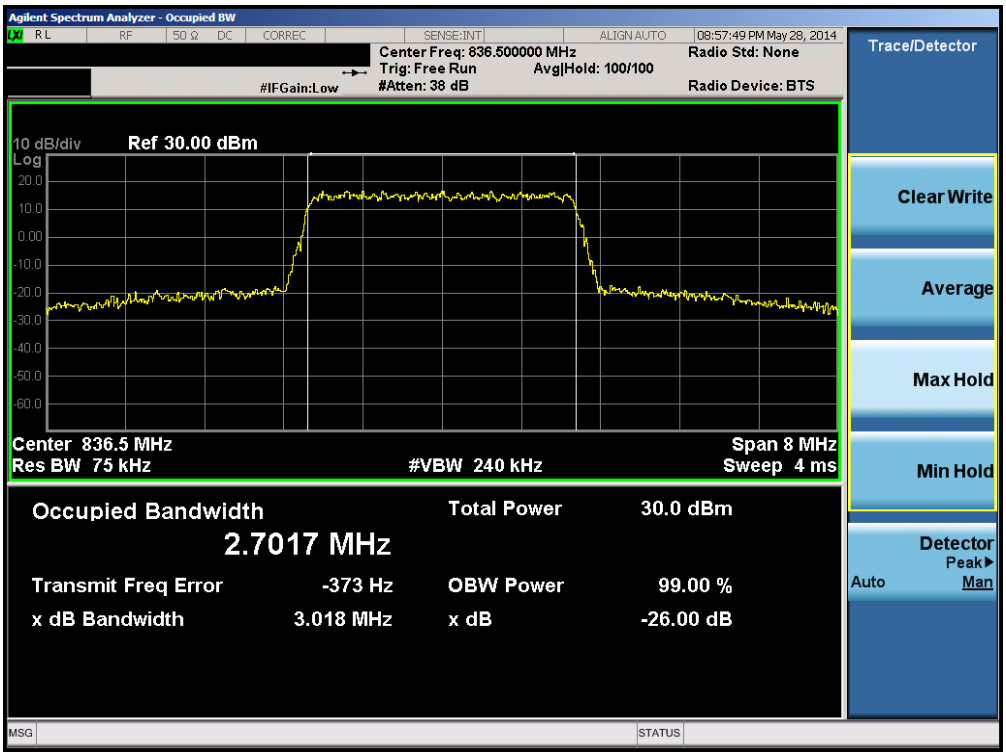


Plot 6-3. Occupied Bandwidth Plot (Band 26 – 3.0MHz QPSK – RB Size 15)



Plot 6-4. Occupied Bandwidth Plot (Band 26 – 3.0MHz 16-QAM – RB Size 15)

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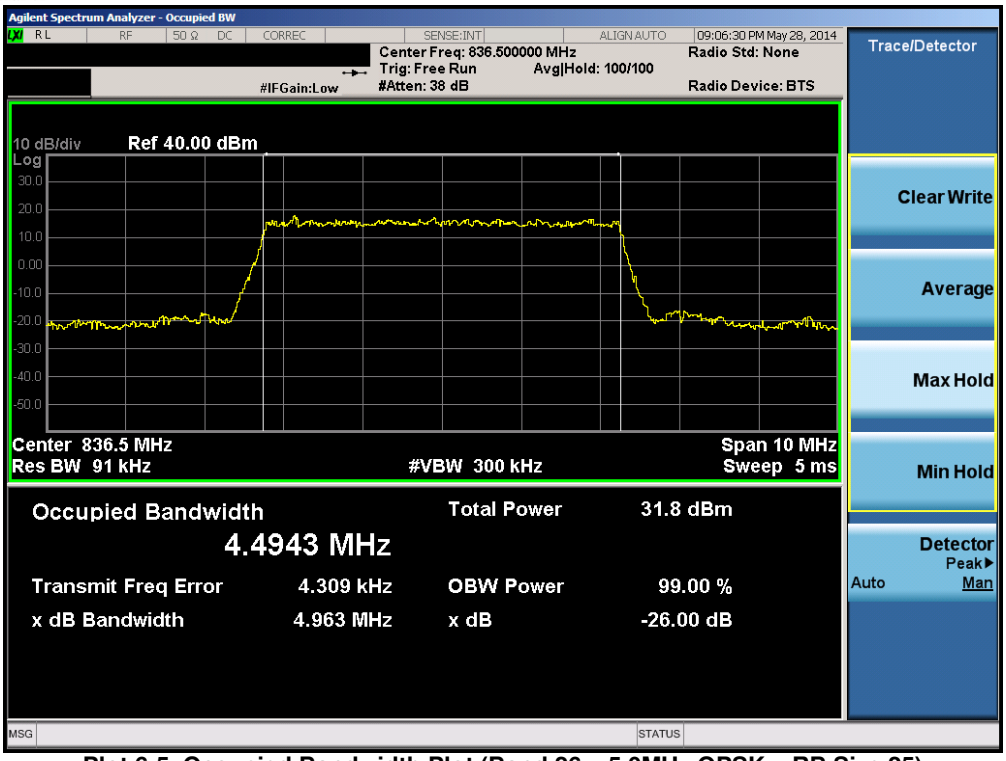

Plot 6-5. Occupied Bandwidth Plot (Band 26 – 5.0MHz QPSK – RB Size 25)

Plot 6-6. Occupied Bandwidth Plot (Band 26 – 5.0MHz 16-QAM – RB Size 25)

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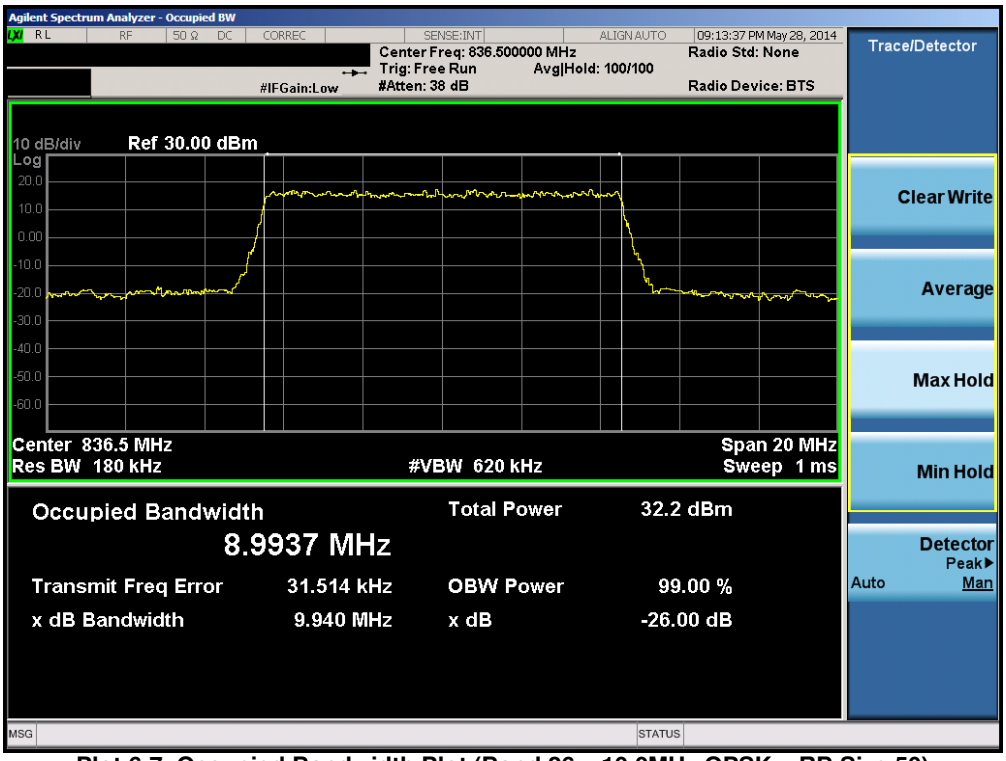

Plot 6-7. Occupied Bandwidth Plot (Band 26 – 10.0MHz QPSK – RB Size 50)

Plot 6-8. Occupied Bandwidth Plot (Band 26 – 10.0MHz 16-QAM – RB Size 50)

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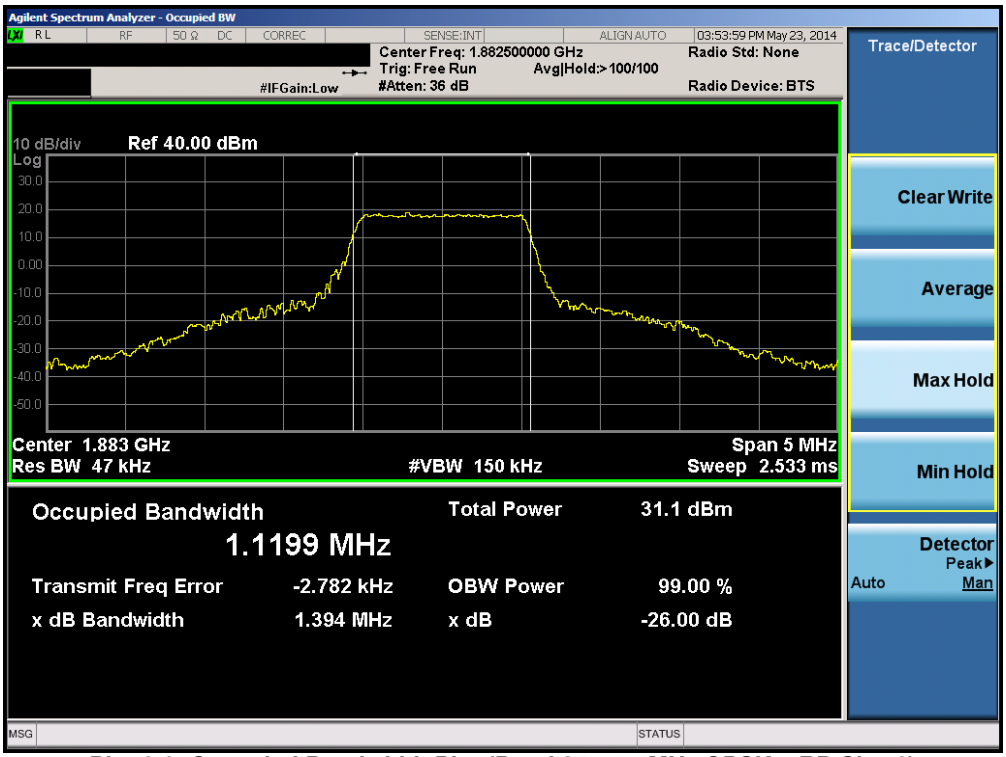
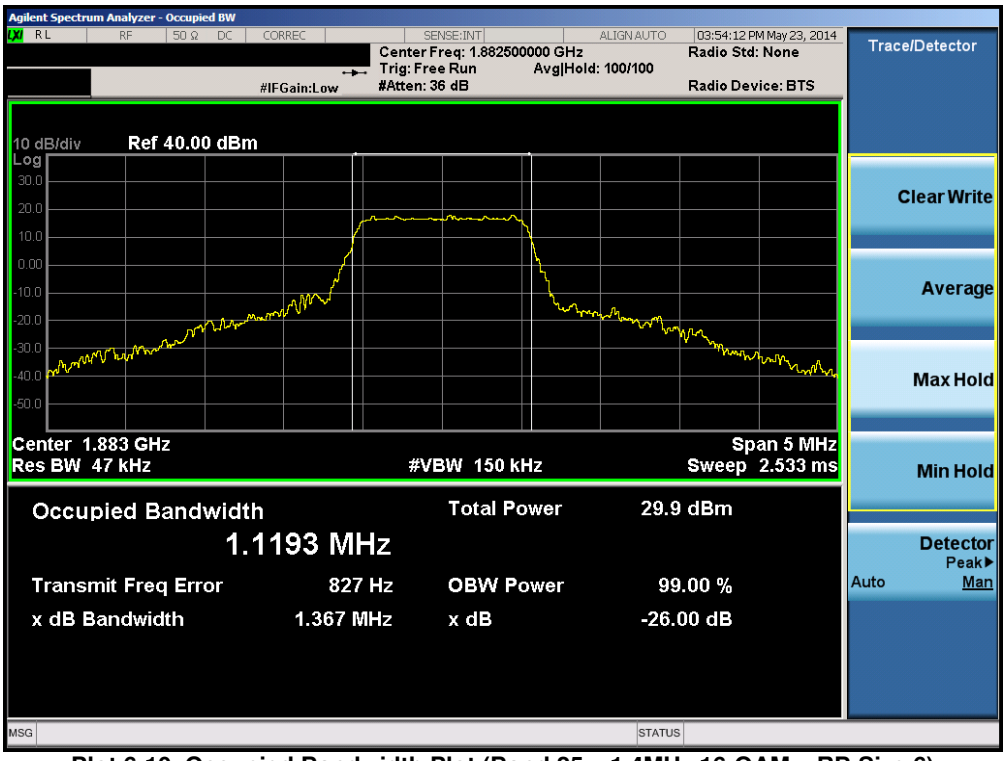


Plot 6-9. Occupied Bandwidth Plot (Band 25 – 1.4MHz QPSK – RB Size 6)



Plot 6-10. Occupied Bandwidth Plot (Band 25 – 1.4MHz 16-QAM – RB Size 6)

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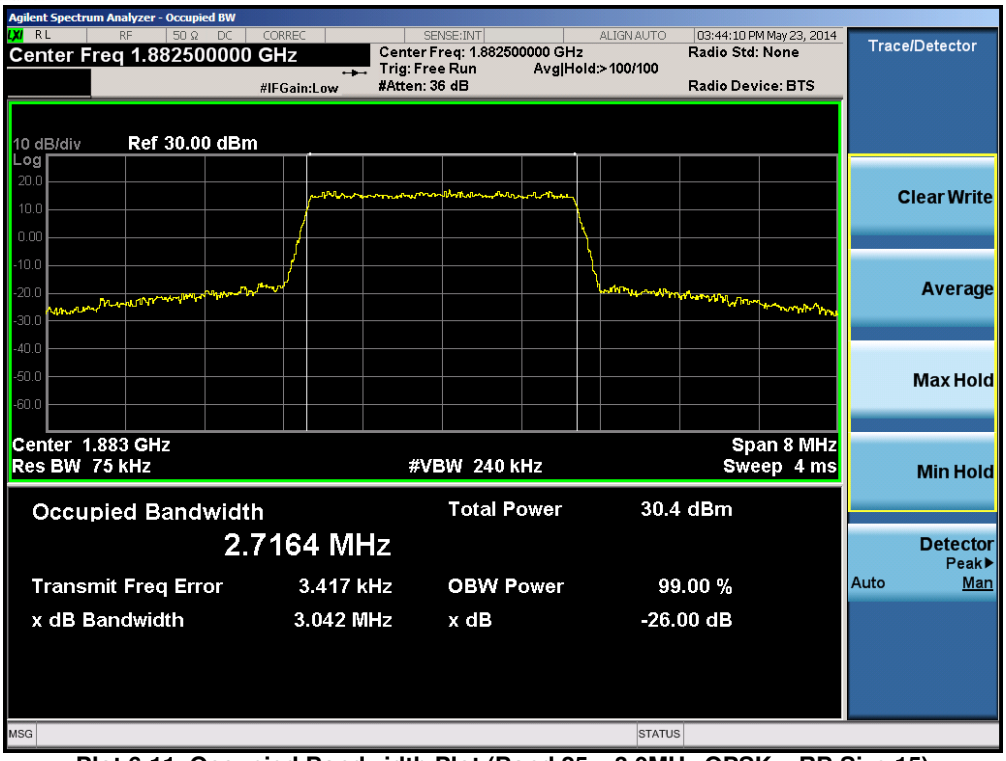
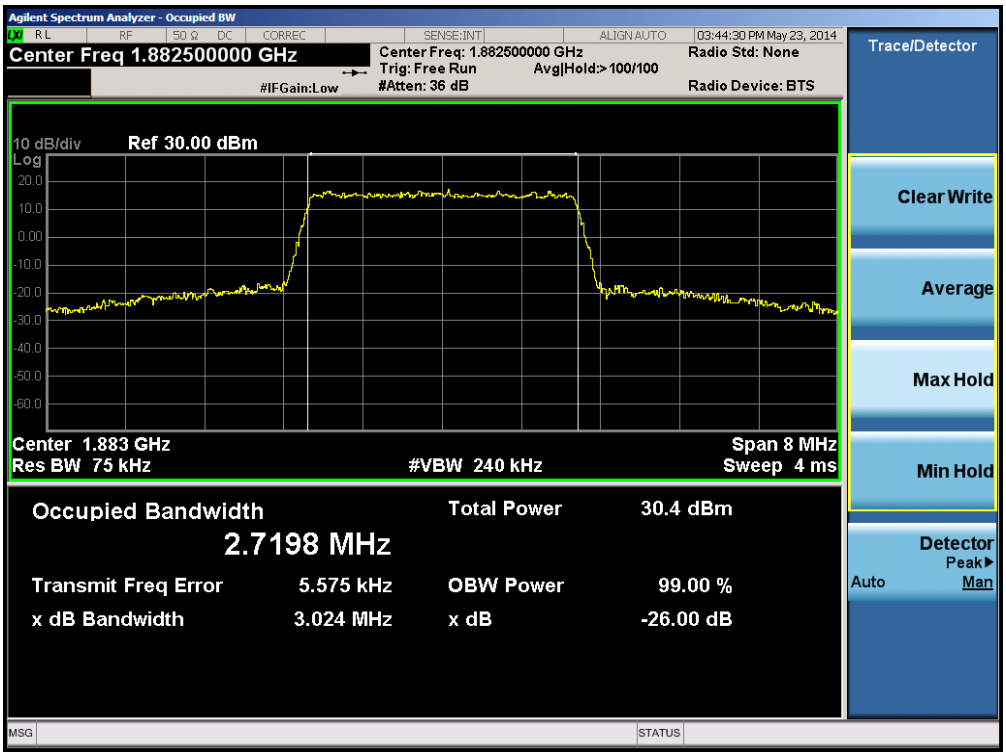


Plot 6-11. Occupied Bandwidth Plot (Band 25 – 3.0MHz QPSK – RB Size 15)



Plot 6-12. Occupied Bandwidth Plot (Band 25 – 3.0MHz 16-QAM – RB Size 15)

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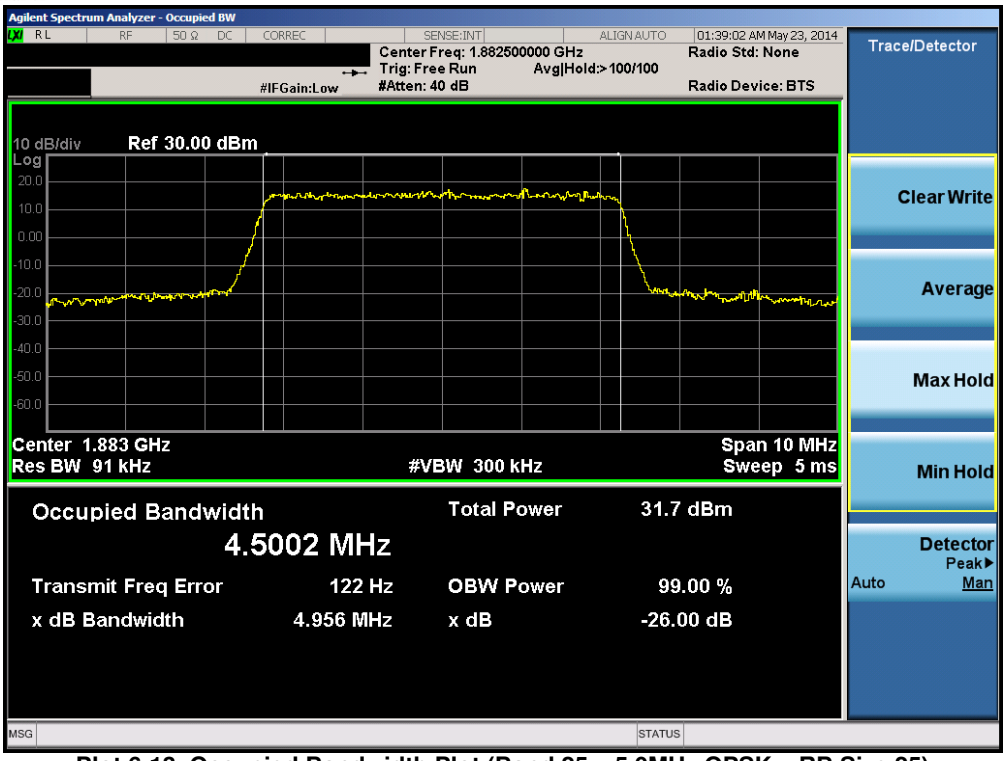
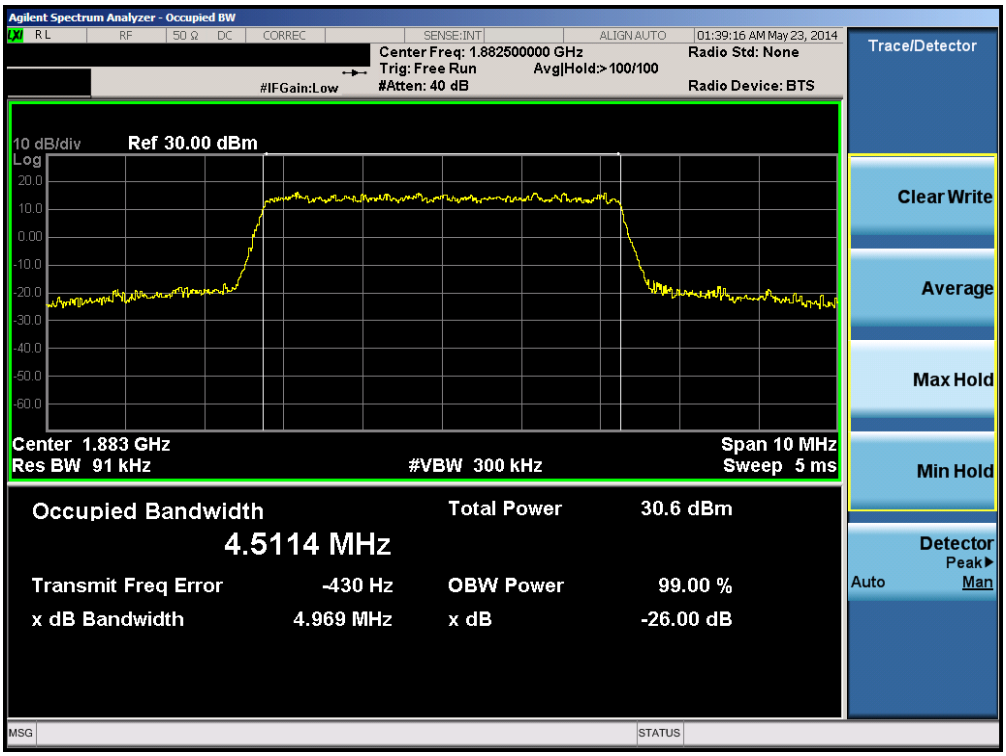


Plot 6-13. Occupied Bandwidth Plot (Band 25 – 5.0MHz QPSK – RB Size 25)



Plot 6-14. Occupied Bandwidth Plot (Band 25 – 5.0MHz 16-QAM – RB Size 25)

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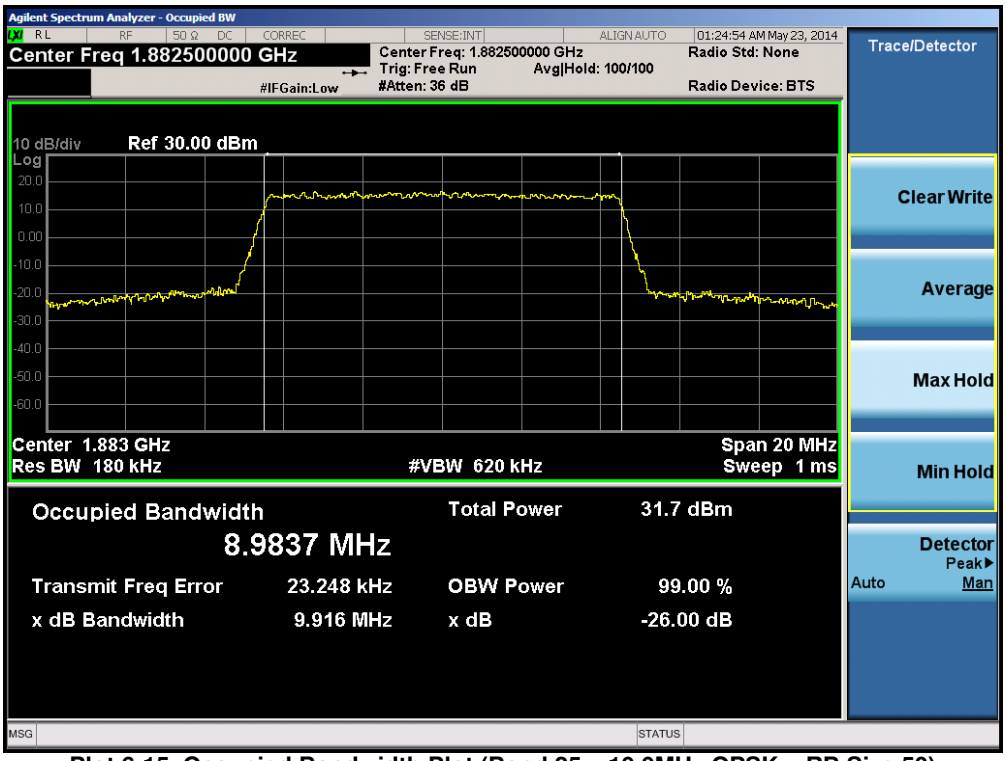
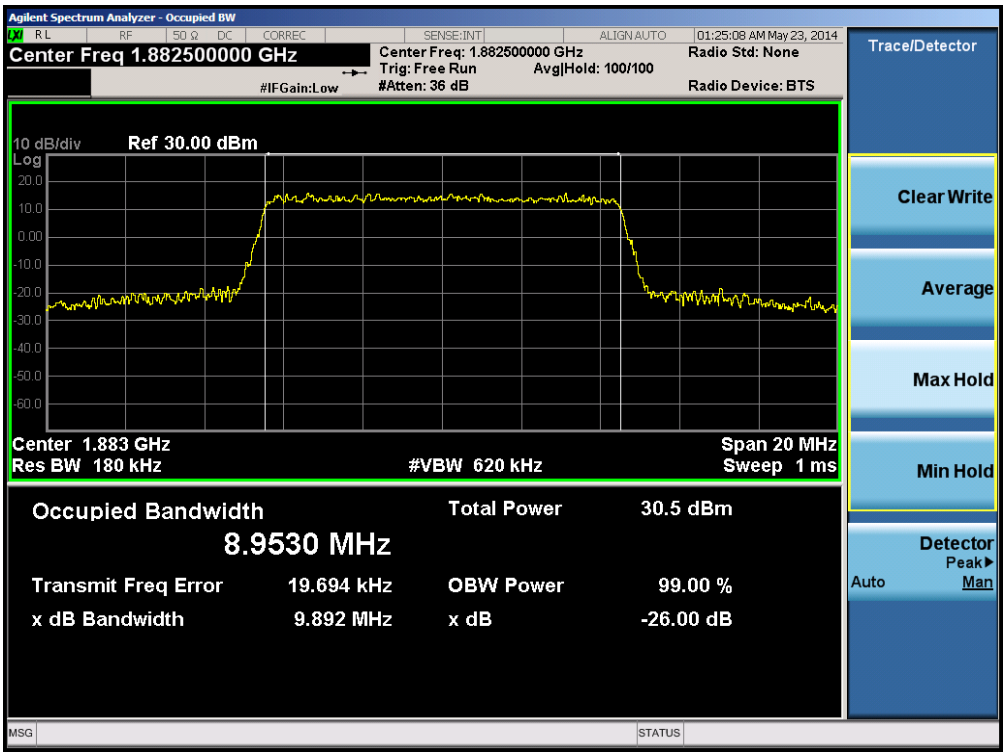


Plot 6-15. Occupied Bandwidth Plot (Band 25 – 10.0MHz QPSK – RB Size 50)



Plot 6-16. Occupied Bandwidth Plot (Band 25 – 10.0MHz 16-QAM – RB Size 50)

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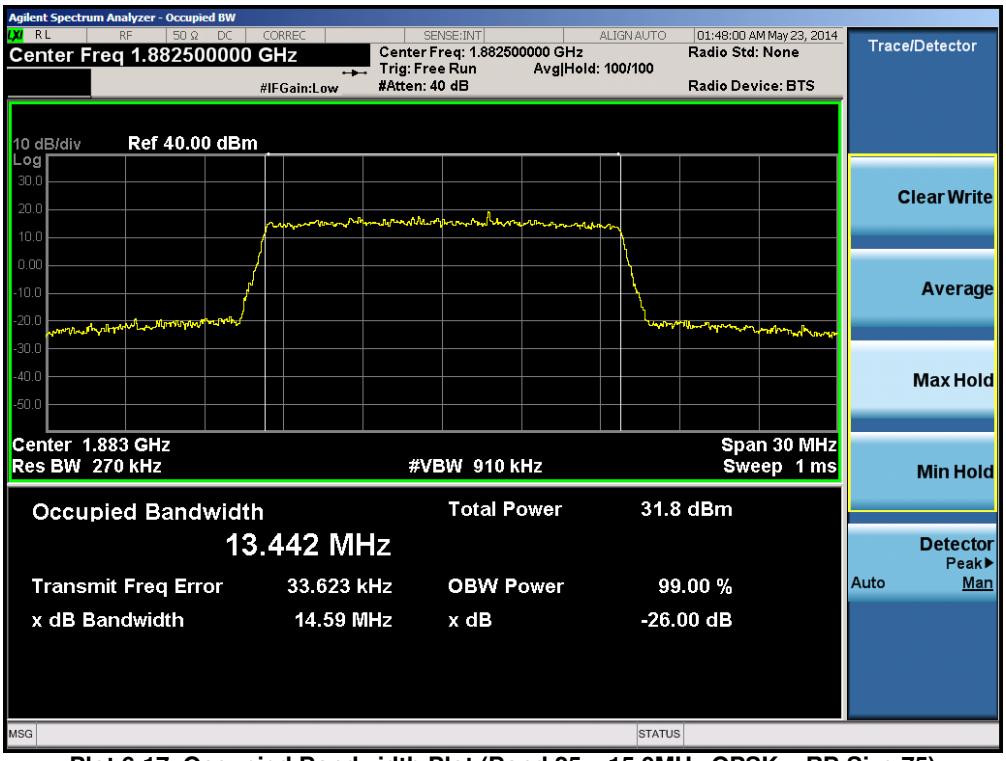
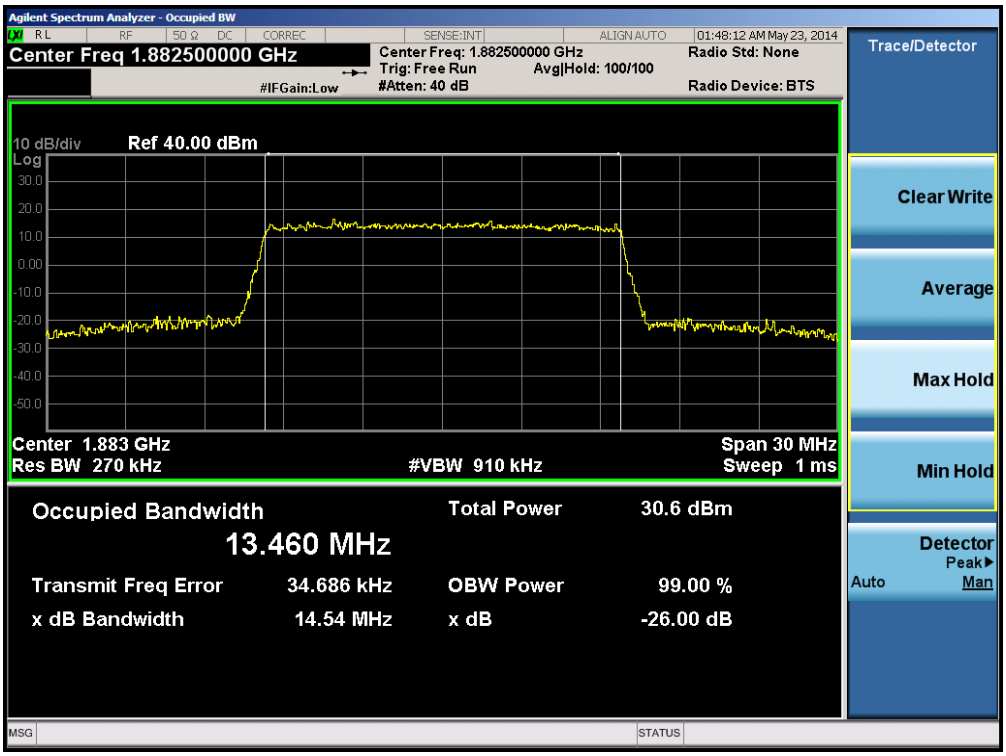


Plot 6-17. Occupied Bandwidth Plot (Band 25 – 15.0MHz QPSK – RB Size 75)



Plot 6-18. Occupied Bandwidth Plot (Band 25 – 15.0MHz 16-QAM – RB Size 75)

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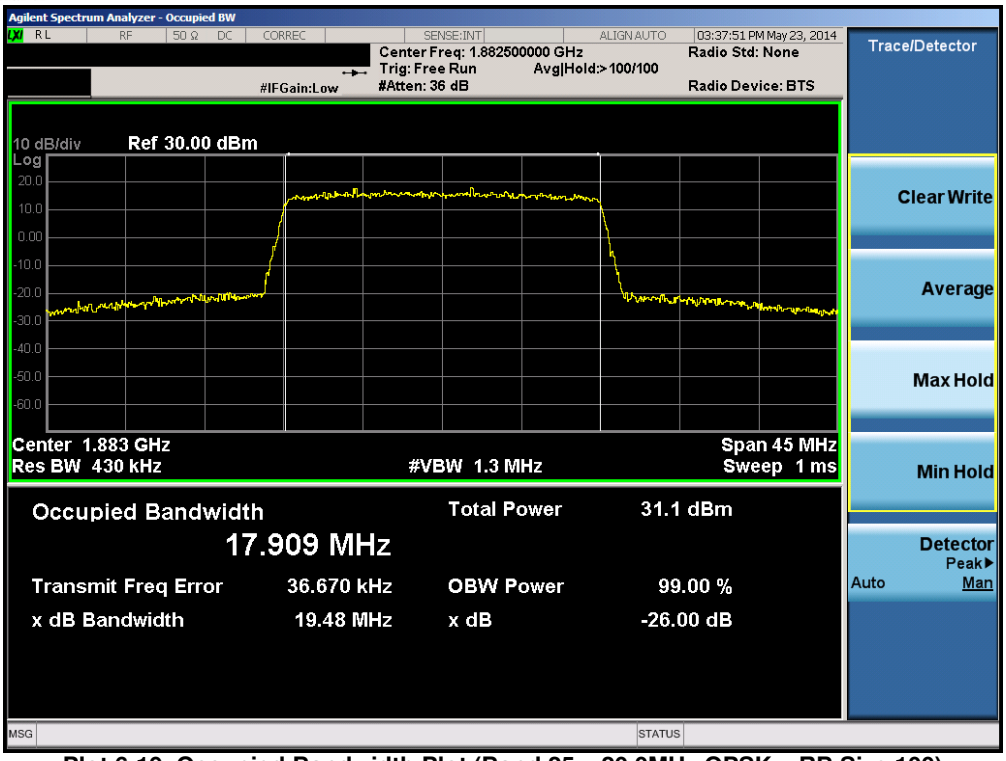
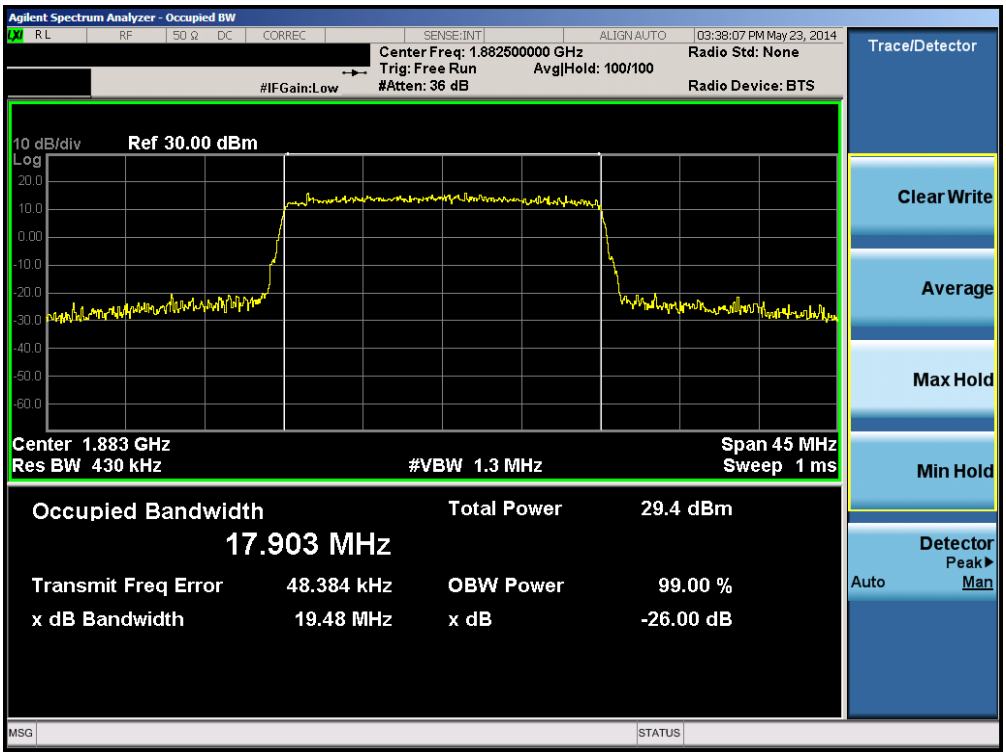


Plot 6-19. Occupied Bandwidth Plot (Band 25 – 20.0MHz QPSK – RB Size 100)



Plot 6-20. Occupied Bandwidth Plot (Band 25 – 20.0MHz 16-QAM – RB Size 100)

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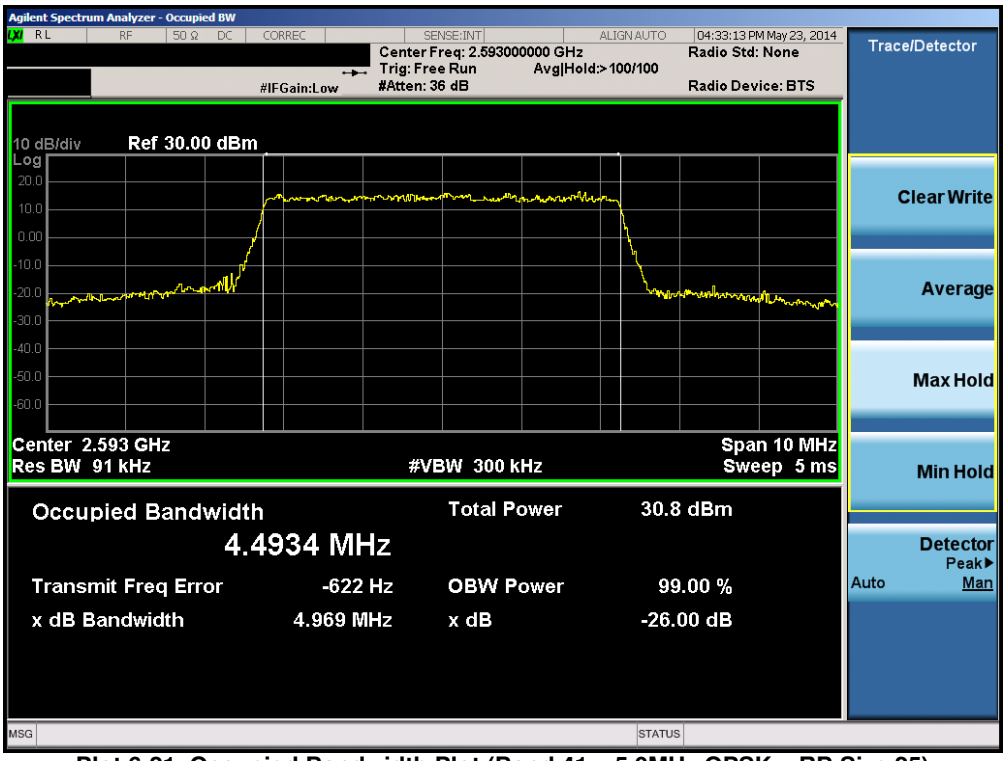
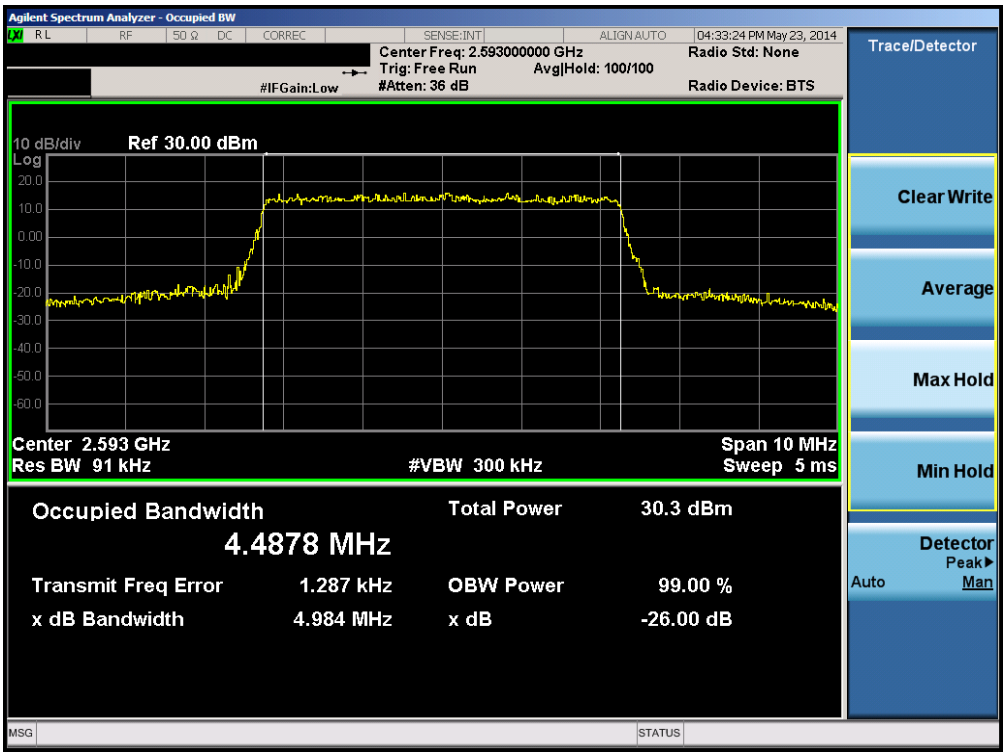


Plot 6-21. Occupied Bandwidth Plot (Band 41 – 5.0MHz QPSK – RB Size 25)



Plot 6-22. Occupied Bandwidth Plot (Band 41 – 5.0MHz 16-QAM – RB Size 25)

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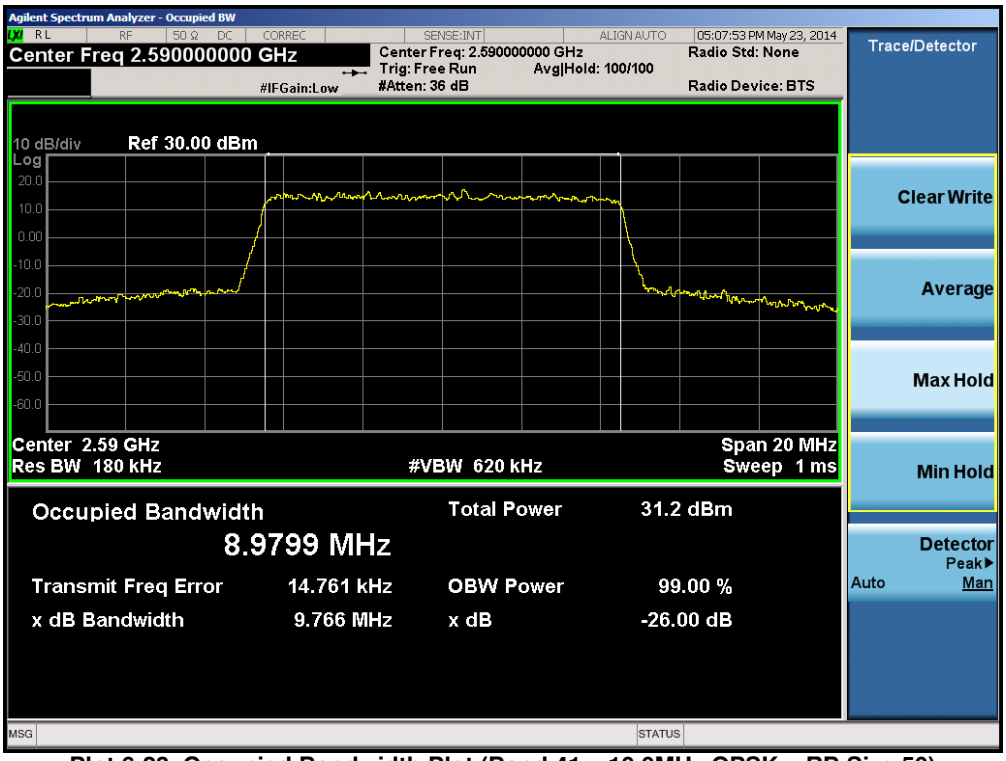
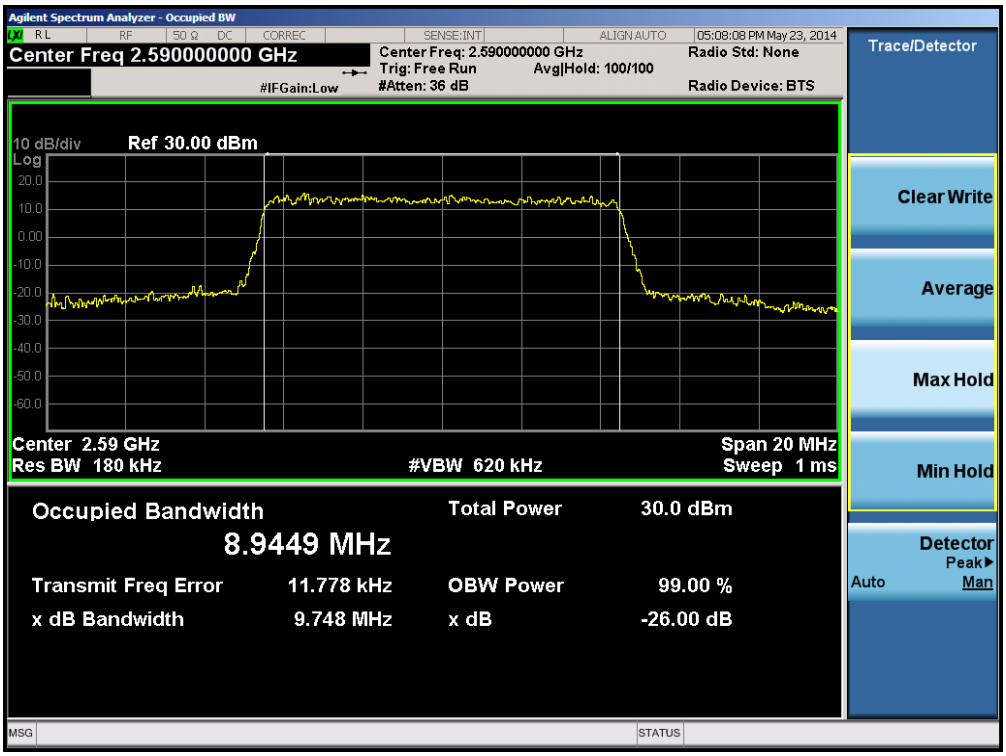


Plot 6-23. Occupied Bandwidth Plot (Band 41 – 10.0MHz QPSK – RB Size 50)



Plot 6-24. Occupied Bandwidth Plot (Band 41 – 10.0MHz 16-QAM – RB Size 50)

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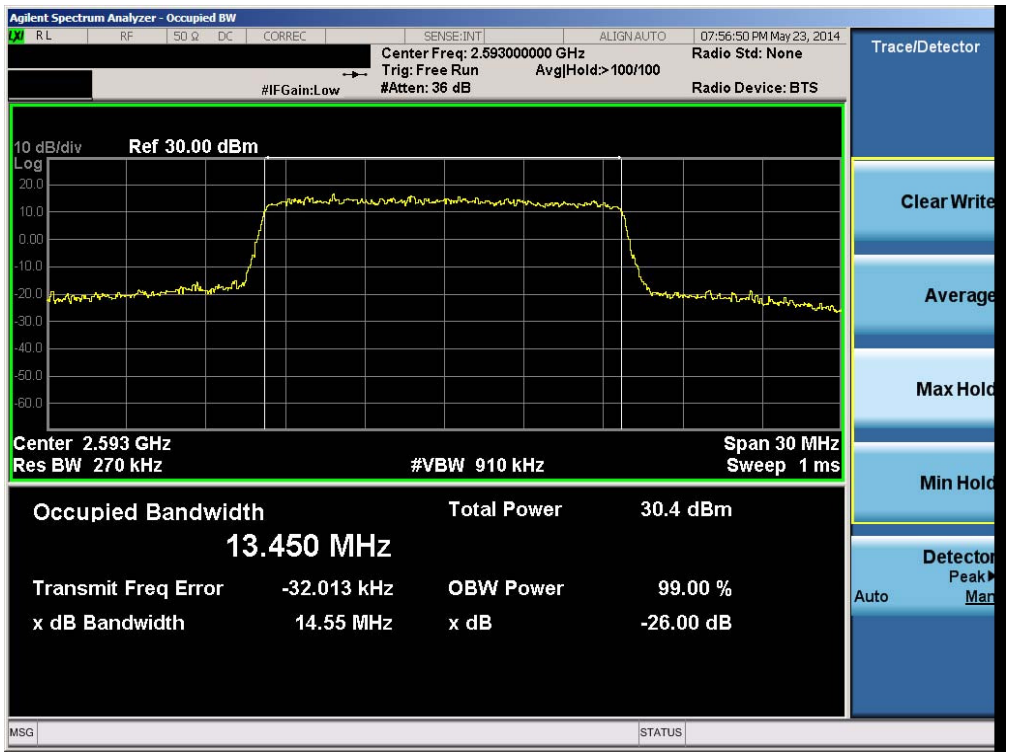
Plot 6-25. Occupied Bandwidth Plot (Band 41 – 15.0MHz QPSK – RB Size 75)



Plot 6-26. Occupied Bandwidth Plot (Band 41 – 15.0MHz 16-QAM – RB Size 75)

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Plot 6-27. Occupied Bandwidth Plot (Band 41 – 20.0MHz QPSK – RB Size 100)

Plot 6-28. Occupied Bandwidth Plot (Band 41 – 20.0MHz 16-QAM – RB Size 100)

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6.3 Spurious and Harmonic Emissions at Antenna Terminal

§2.1051 §22.917(a) §24.238(a) §27.53(l)

Test Overview

The level of the carrier and the various conducted spurious and harmonic frequencies is measured by means of a calibrated spectrum analyzer. The spectrum is scanned from the lowest frequency generated in the equipment up to a frequency including its 10th harmonic. All out of band emissions are measured with a spectrum analyzer connected to the antenna terminal of the EUT while the EUT is operating at its maximum duty cycle, at maximum power, and at the appropriate frequencies. All data rates were investigated to determine the worst case configuration. All modes of operation were investigated and the worst case configuration results are reported in this section.

The minimum permissible attenuation level of any spurious emission is 43 + $\log_{10}(P_{[Watts]})$, where P is the transmitter power in Watts. For Band 41, the minimum permissible attenuation level of any spurious emission is 55 + $\log_{10}(P_{[Watts]})$.

Test Procedure Used

KDB 971168 v02r01 – Section 6.0

Test Settings

1. Start frequency was set to 30MHz and stop frequency was set to at least 10 * the fundamental frequency (separated into at least two plots per channel)
2. Detector = RMS
3. Trace mode = max hold
4. Sweep time = auto couple
5. The trace was allowed to stabilize
6. Please see test notes below for RBW and VBW settings

Test Setup

The EUT and measurement equipment were set up as shown in the diagram below.

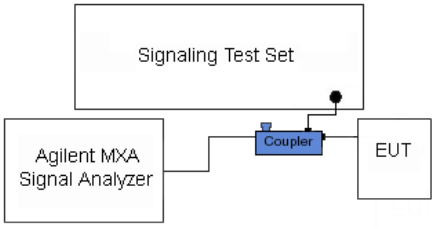

Figure 6-2. Test Instrument & Measurement Setup

Test Notes

Compliance with the applicable limits is based on the use of measurement instrumentation employing a resolution bandwidth of 100 kHz or greater for frequencies less than 1 GHz and 1 MHz or greater for frequencies greater than 1 GHz. However, in the 1 MHz bands immediately outside and adjacent to the frequency block a resolution bandwidth of at least one percent of the emission bandwidth of the fundamental emission of the transmitter may be employed. The emission bandwidth is defined as the width of the signal between two points, one below the carrier center frequency and one above the carrier center frequency, outside of which all emission are attenuated at least 26 dB below the transmitter power. In addtion, Channel Power plots are provided incase the emissions are unable to comply in the swept spectrum technique. In those cases, 1MHz Integration plots are provided to show that the conducted spurious emissions are in compliace with the requirements.

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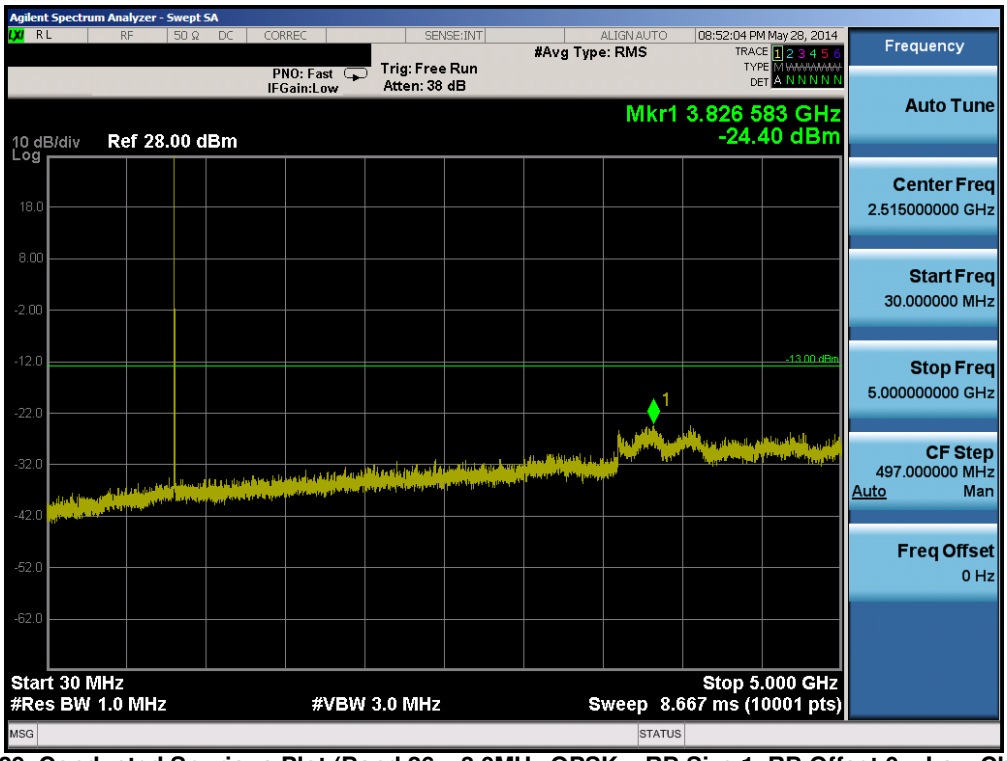
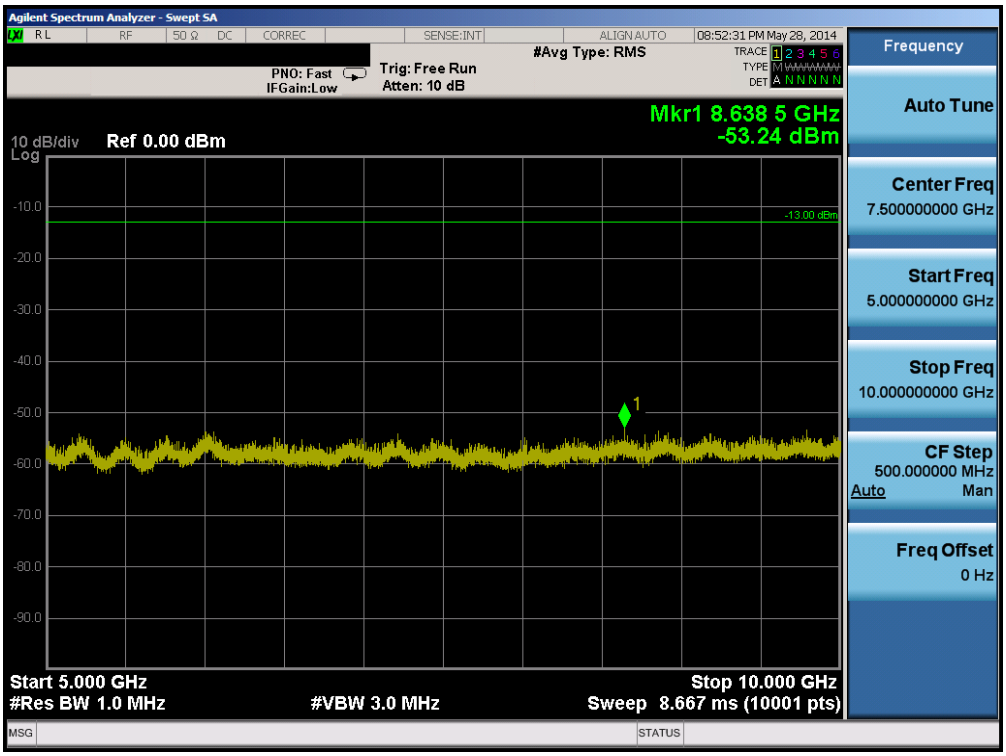


Plot 6-29. Conducted Spurious Plot (Band 26 – 3.0MHz QPSK – RB Size 1, RB Offset 0 – Low Channel)



Plot 6-30. Conducted Spurious Plot (Band 26 – 3.0MHz QPSK – RB Size 1, RB Offset 0 – Low Channel)

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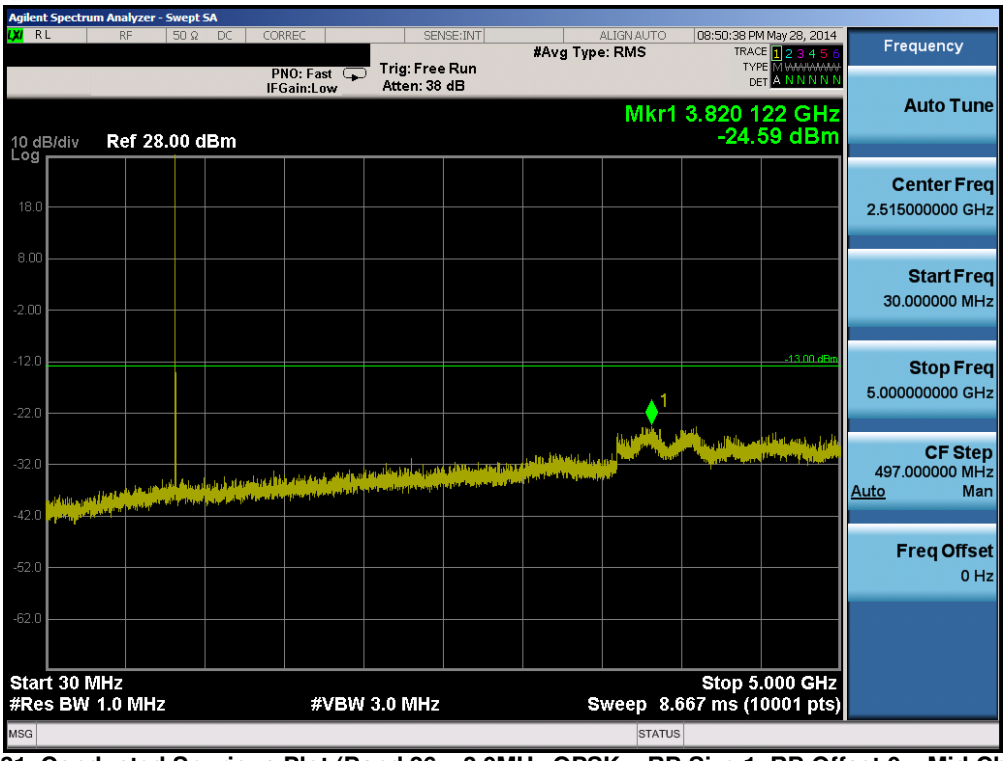
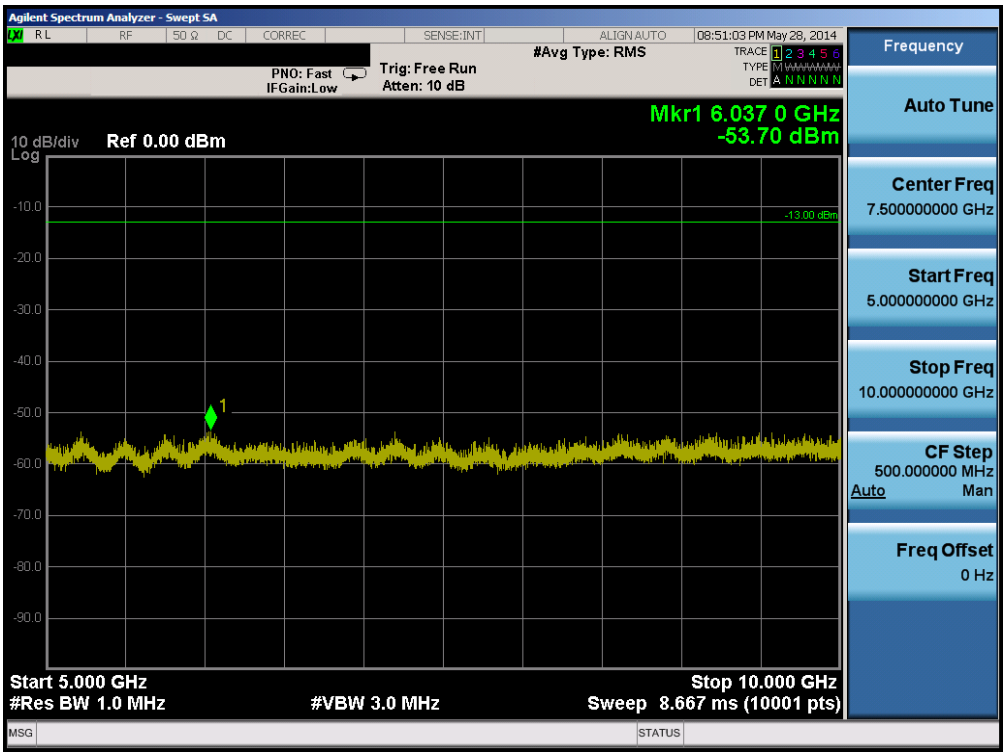


Plot 6-31. Conducted Spurious Plot (Band 26 – 3.0MHz QPSK – RB Size 1, RB Offset 0 – Mid Channel)



Plot 6-32. Conducted Spurious Plot (Band 26 – 3.0MHz QPSK – RB Size 1, RB Offset 0 – Mid Channel)

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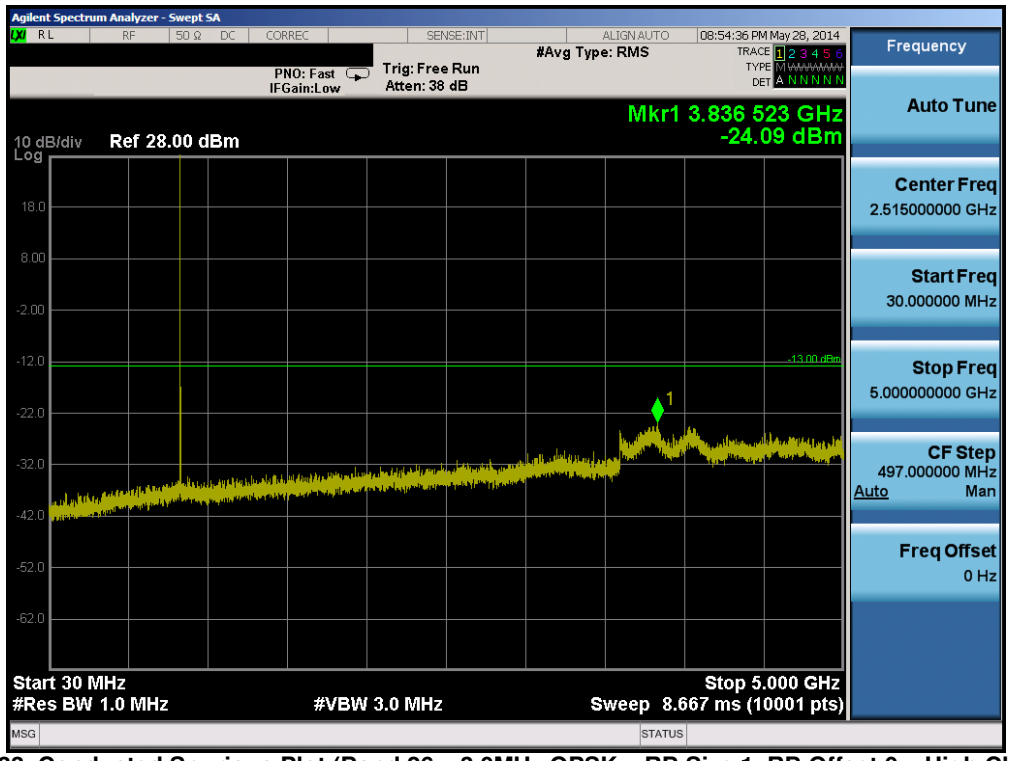
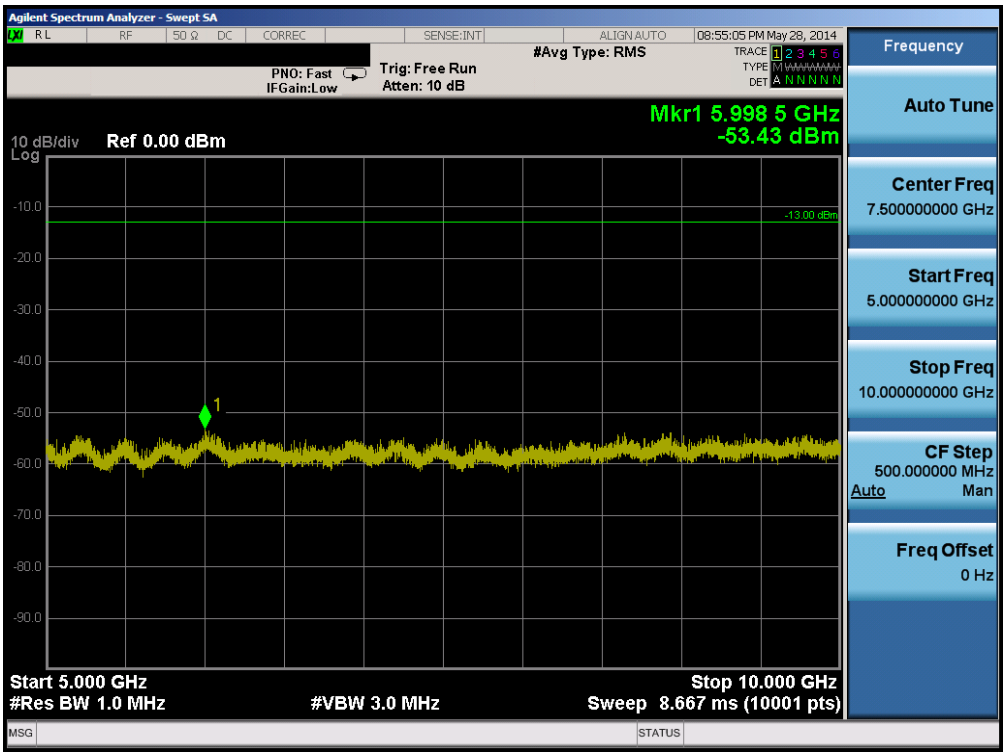


Plot 6-33. Conducted Spurious Plot (Band 26 – 3.0MHz QPSK – RB Size 1, RB Offset 0 – High Channel)



Plot 6-34. Conducted Spurious Plot (Band 26 – 3.0MHz QPSK – RB Size 1, RB Offset 0 – High Channel)

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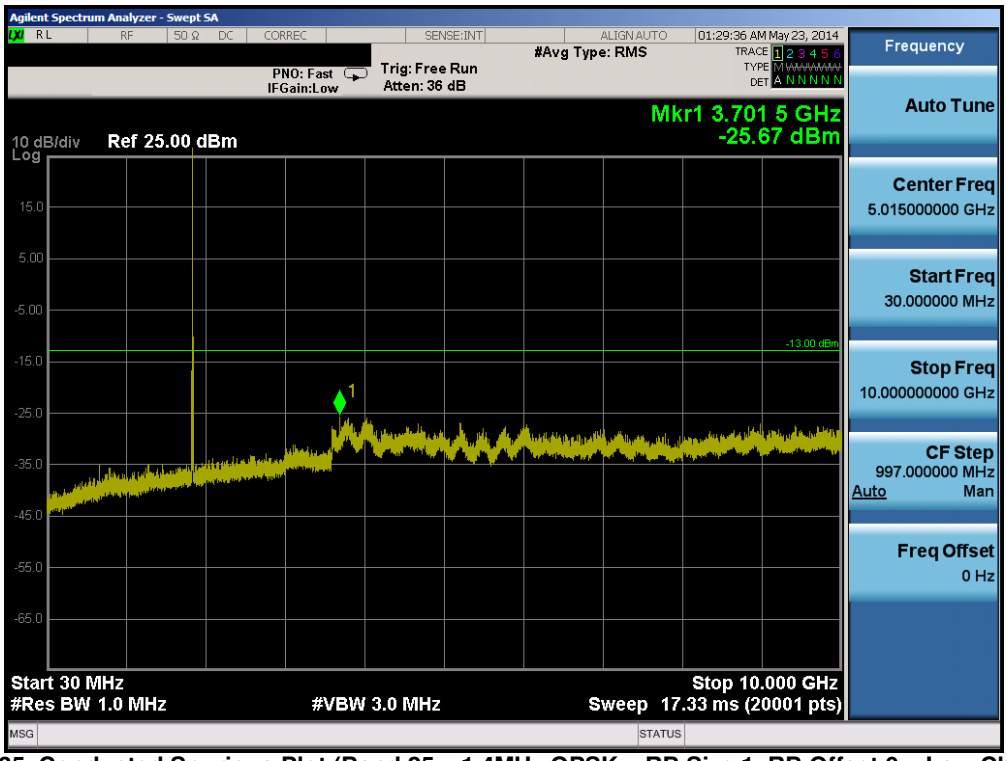
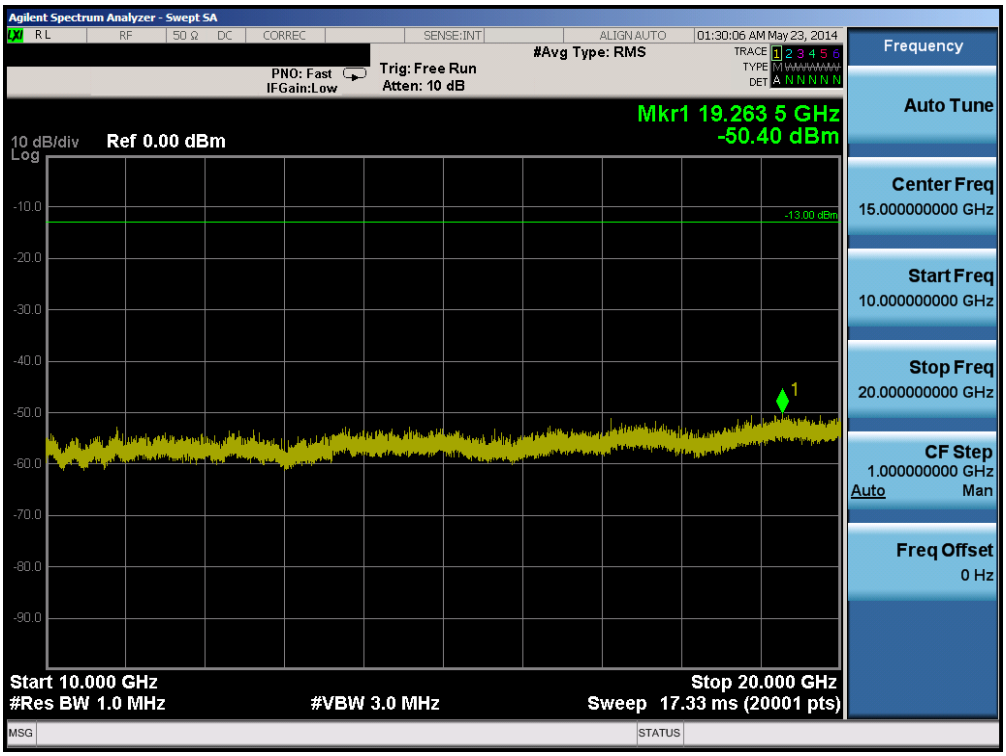


Plot 6-35. Conducted Spurious Plot (Band 25 – 1.4MHz QPSK – RB Size 1, RB Offset 0 – Low Channel)



Plot 6-36. Conducted Spurious Plot (Band 25 – 1.4MHz QPSK – RB Size 1, RB Offset 0 – Low Channel)

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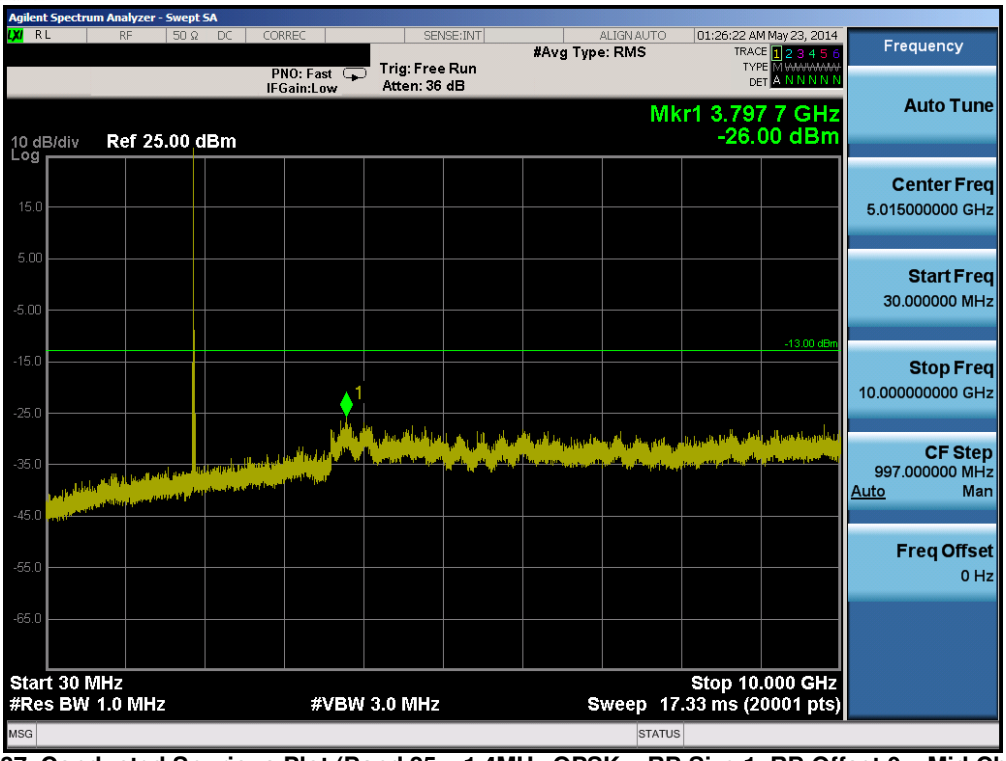
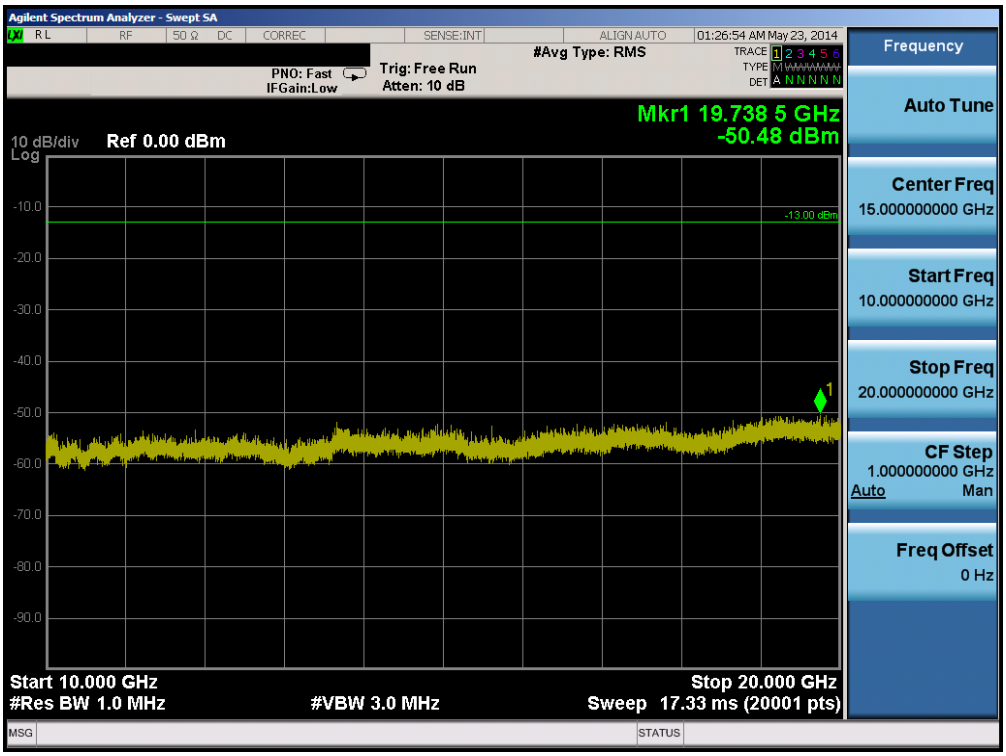


Plot 6-37. Conducted Spurious Plot (Band 25 – 1.4MHz QPSK – RB Size 1, RB Offset 0 – Mid Channel)



Plot 6-38. Conducted Spurious Plot (Band 25 – 1.4MHz QPSK – RB Size 1, RB Offset 0 – Mid Channel)

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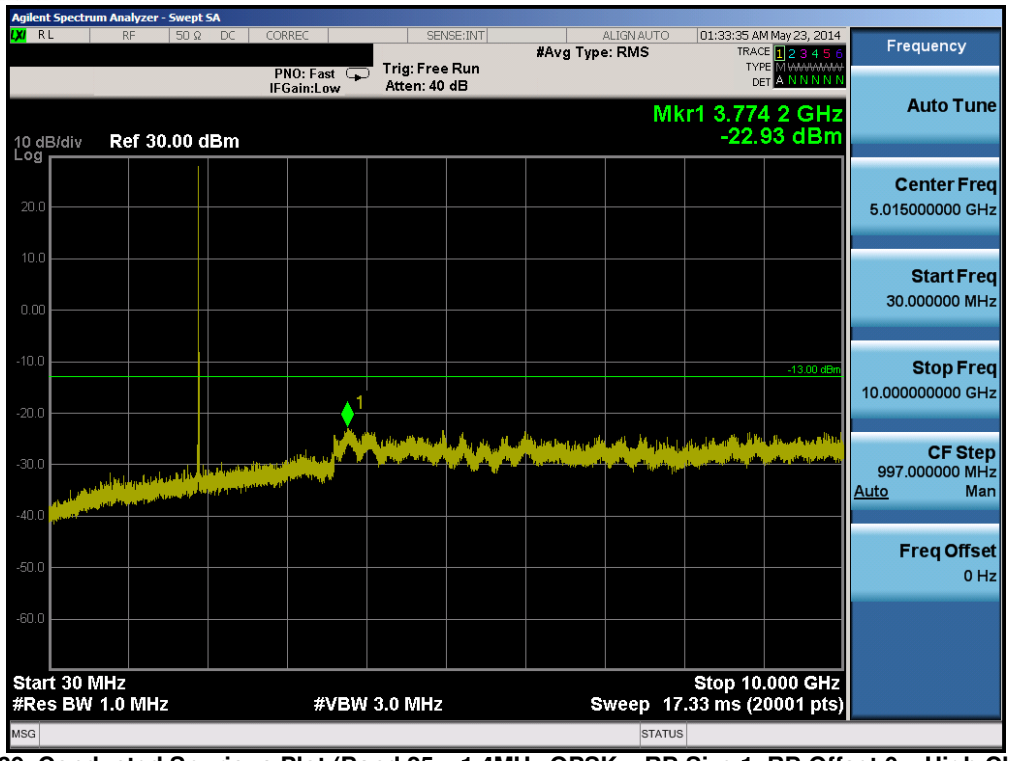
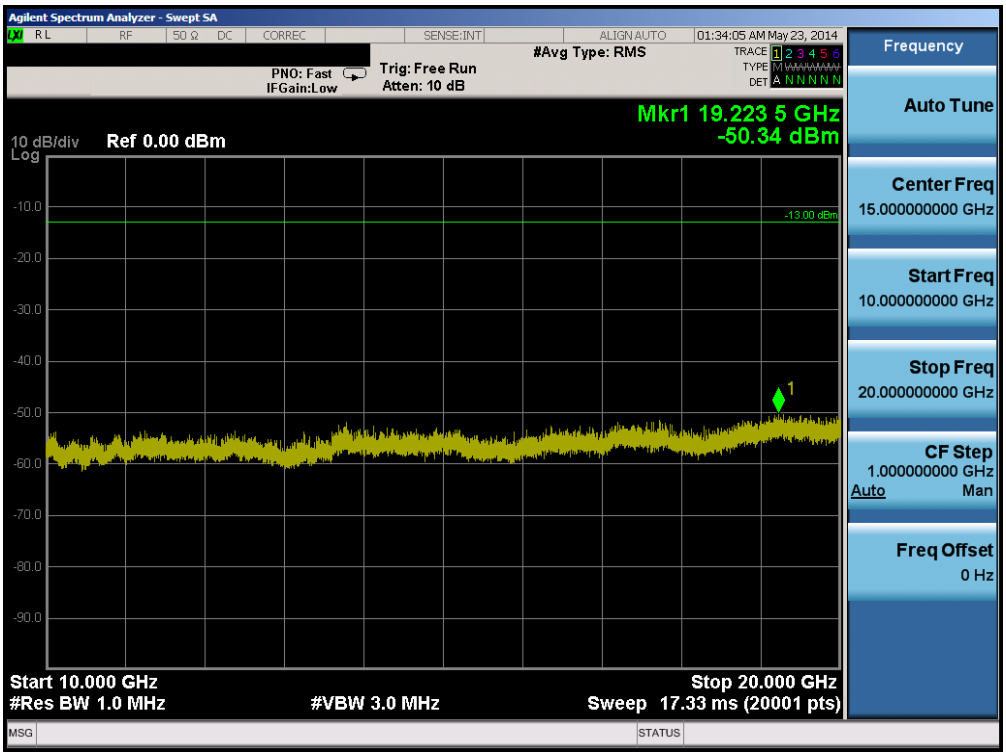


Plot 6-39. Conducted Spurious Plot (Band 25 – 1.4MHz QPSK – RB Size 1, RB Offset 0 – High Channel)



Plot 6-40. Conducted Spurious Plot (Band 25 – 1.4MHz QPSK – RB Size 1, RB Offset 0 – High Channel)

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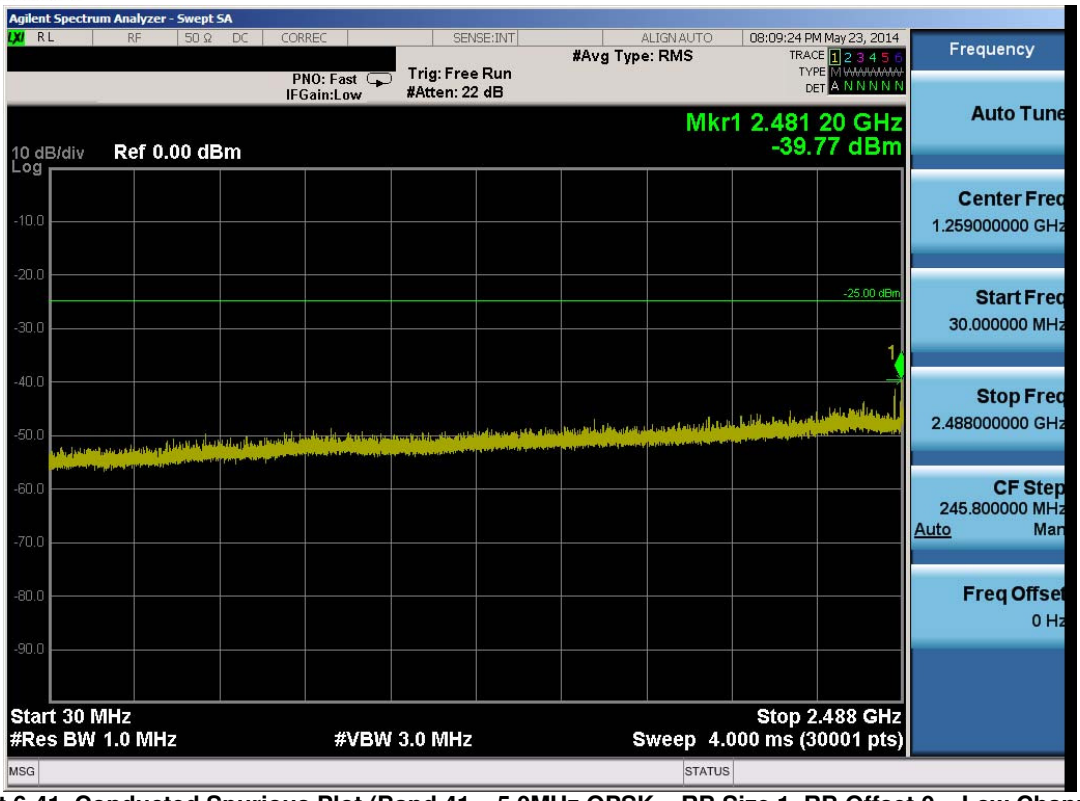
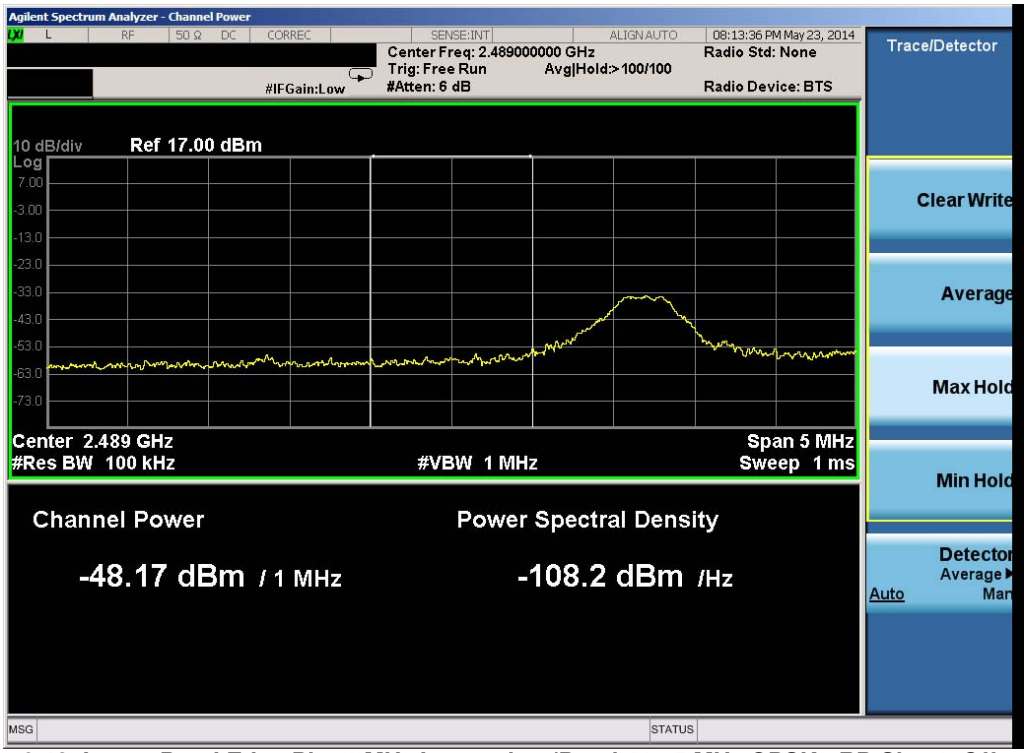


Plot 6-41. Conducted Spurious Plot (Band 41 – 5.0MHz QPSK – RB Size 1, RB Offset 0 – Low Channel)



Plot 6-42. Lower Band Edge Plot 1 MHz Integration (Band 41 - 5 MHz QPSK - RB Size 1, Offset 0)

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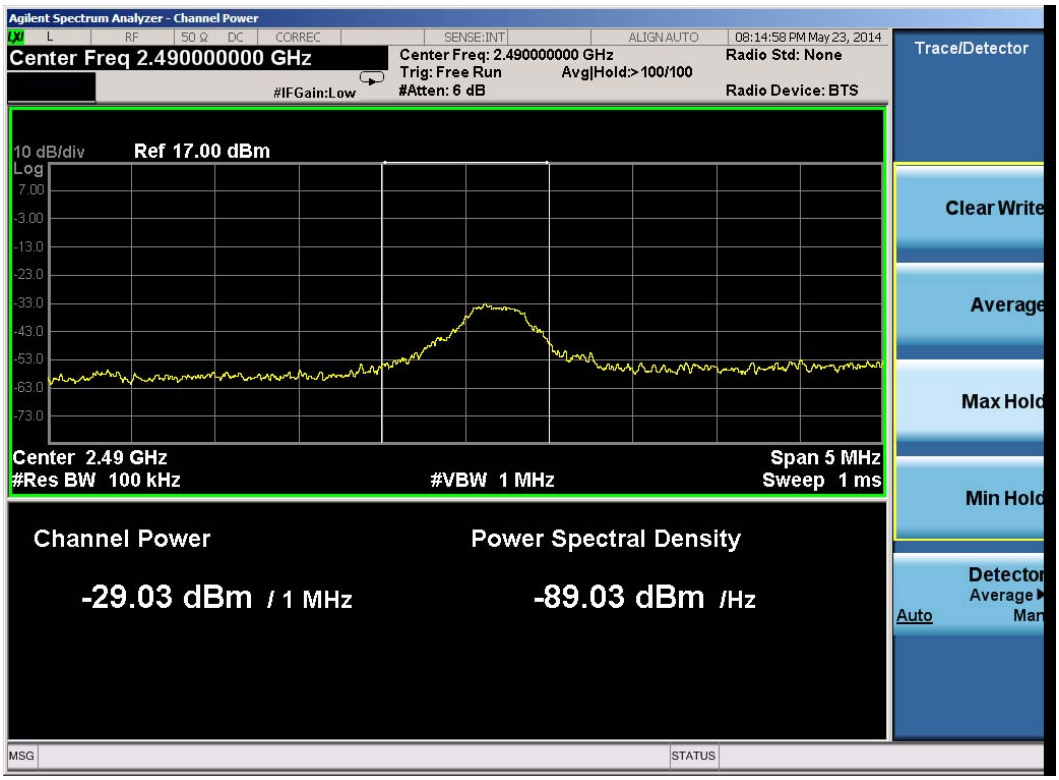
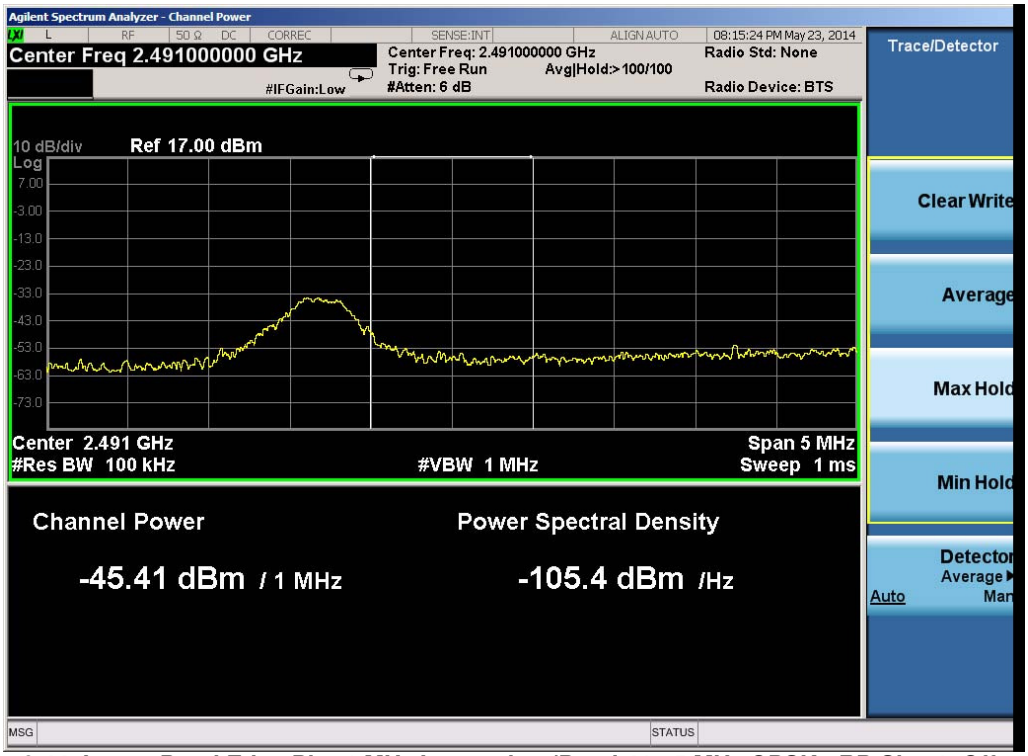


Plot 6-43. Lower Band Edge Plot 1 MHz Integration (Band 41 - 5 MHz QPSK - RB Size 1, Offset 0)



Plot 6-44. Lower Band Edge Plot 1 MHz Integration (Band 41 - 5 MHz QPSK - RB Size 1, Offset 0)

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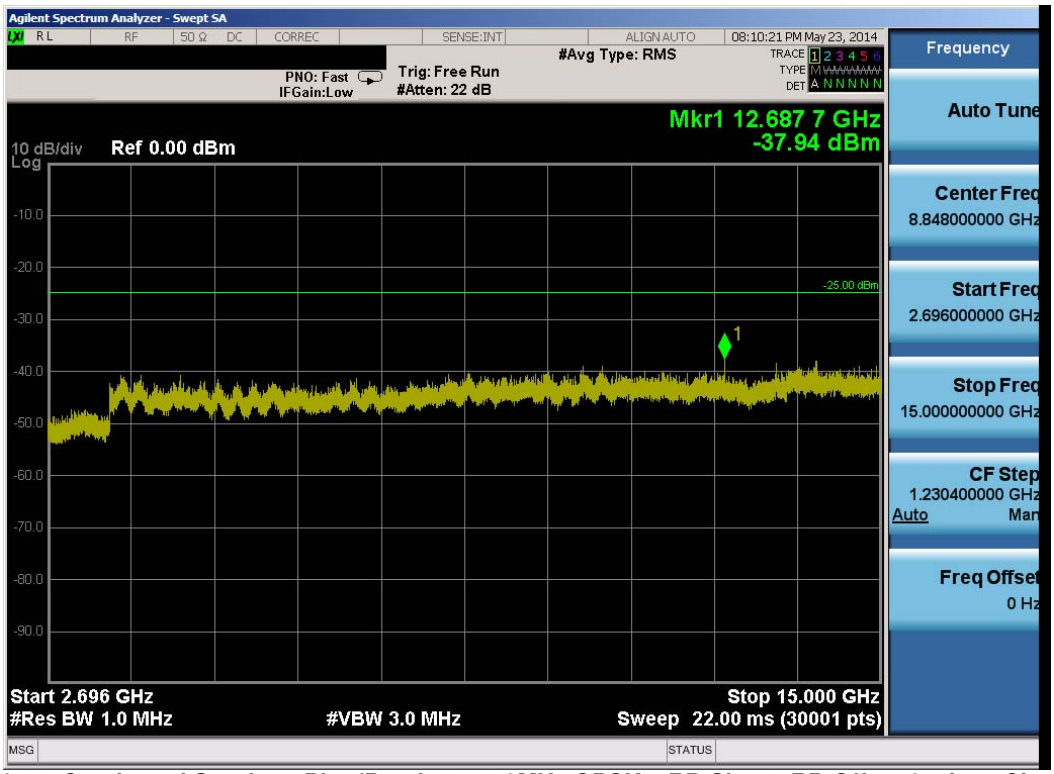
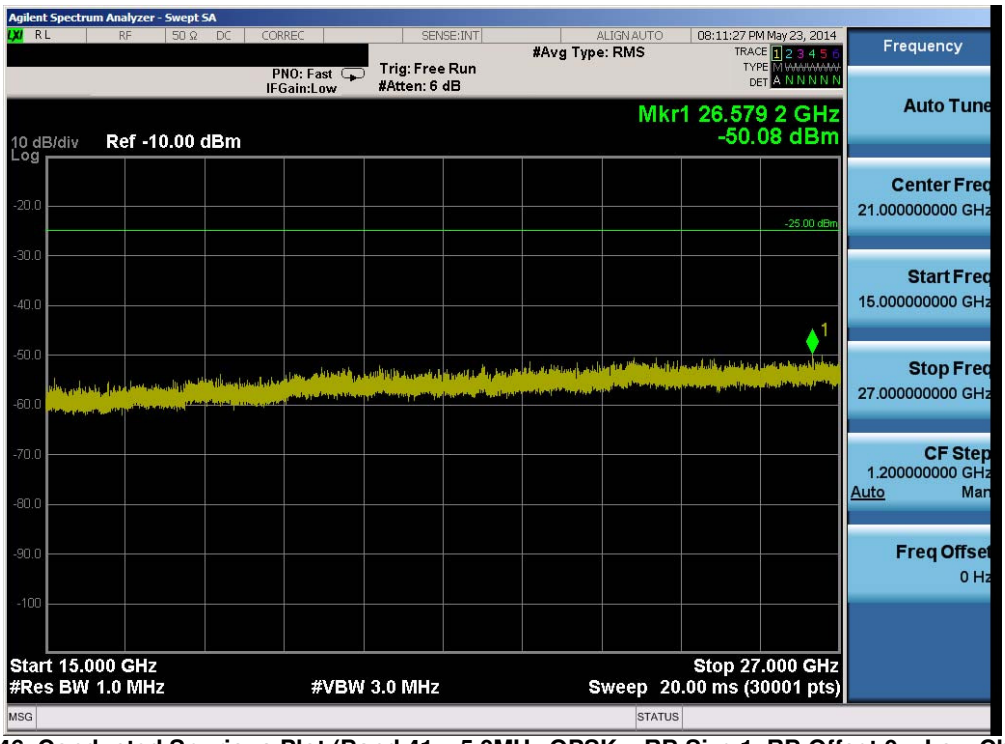


Plot 6-45. Conducted Spurious Plot (Band 41 – 5.0MHz QPSK – RB Size 1, RB Offset 0 – Low Channel)



Plot 6-46. Conducted Spurious Plot (Band 41 – 5.0MHz QPSK – RB Size 1, RB Offset 0 – Low Channel)

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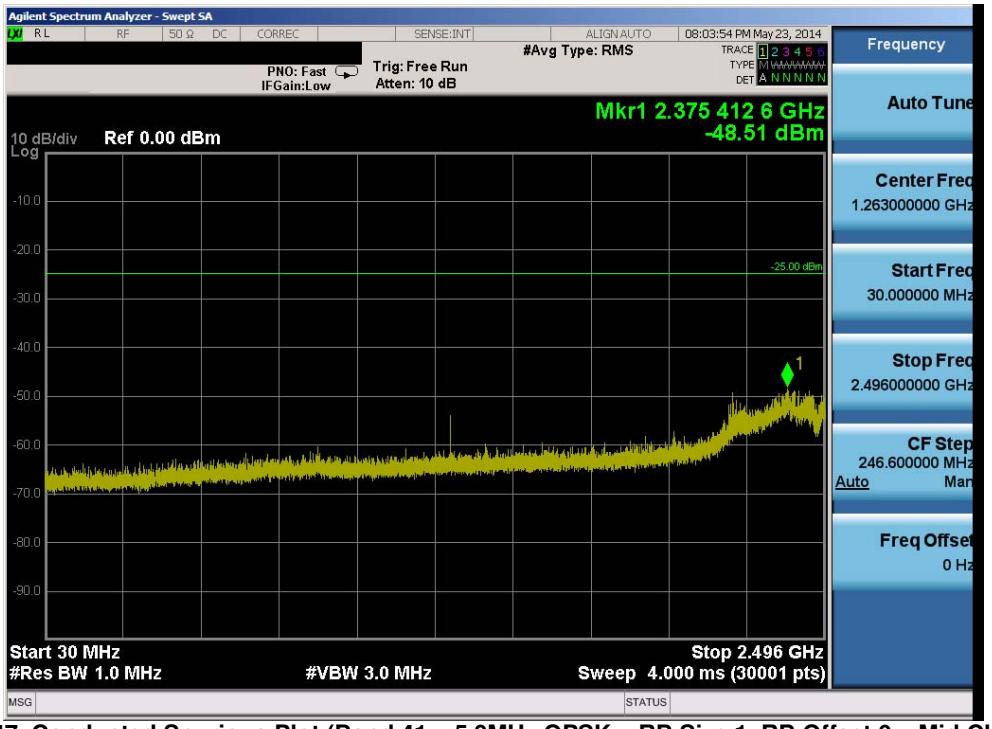
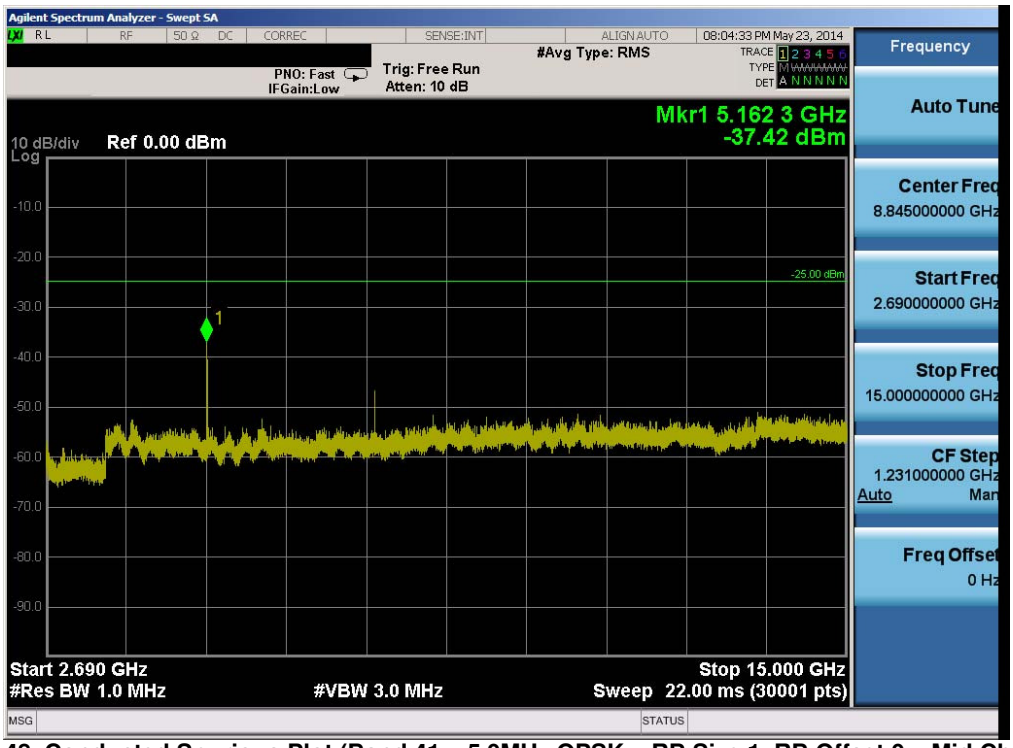


Plot 6-47. Conducted Spurious Plot (Band 41 – 5.0MHz QPSK – RB Size 1, RB Offset 0 – Mid Channel)



Plot 6-48. Conducted Spurious Plot (Band 41 – 5.0MHz QPSK – RB Size 1, RB Offset 0 – Mid Channel)

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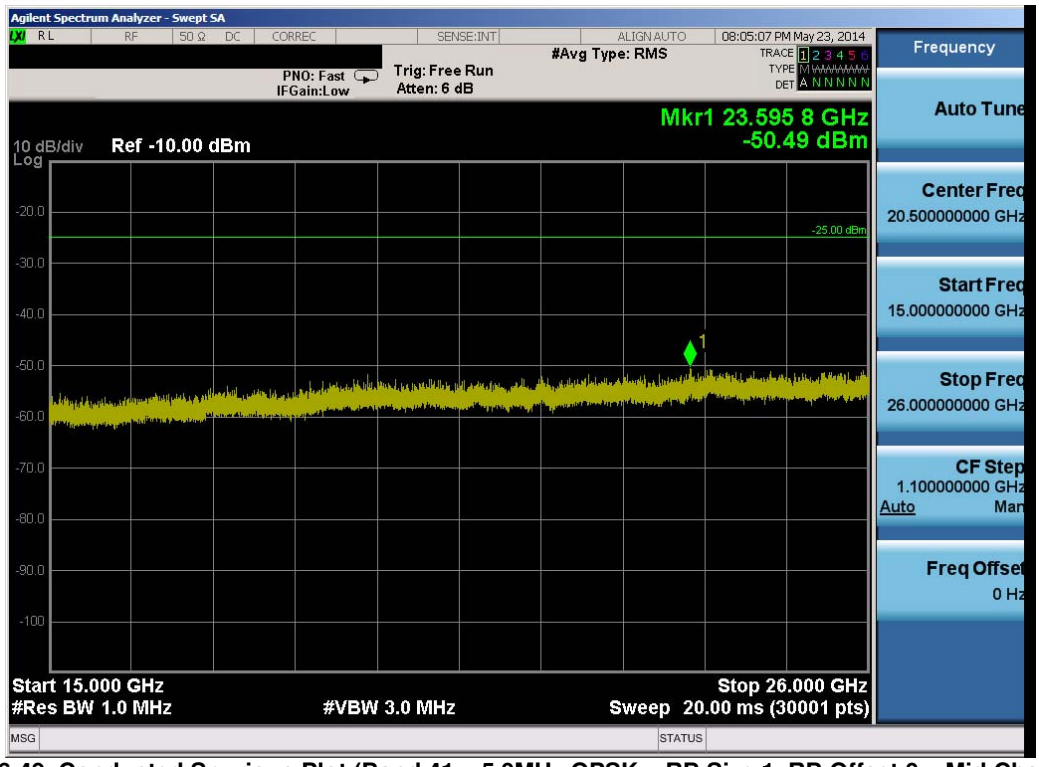
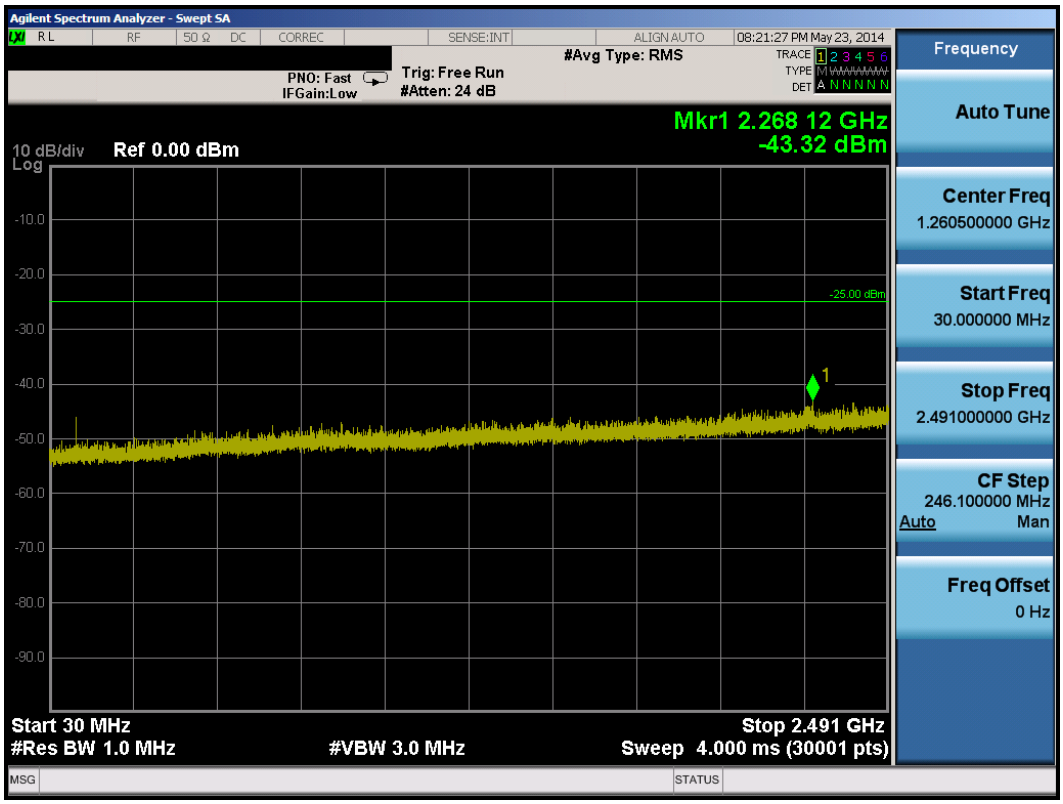


Plot 6-49. Conducted Spurious Plot (Band 41 – 5.0MHz QPSK – RB Size 1, RB Offset 0 – Mid Channel)



Plot 6-50. Conducted Spurious Plot (Band 41 – 5.0MHz QPSK – RB Size 1, RB Offset 0 – High Channel)

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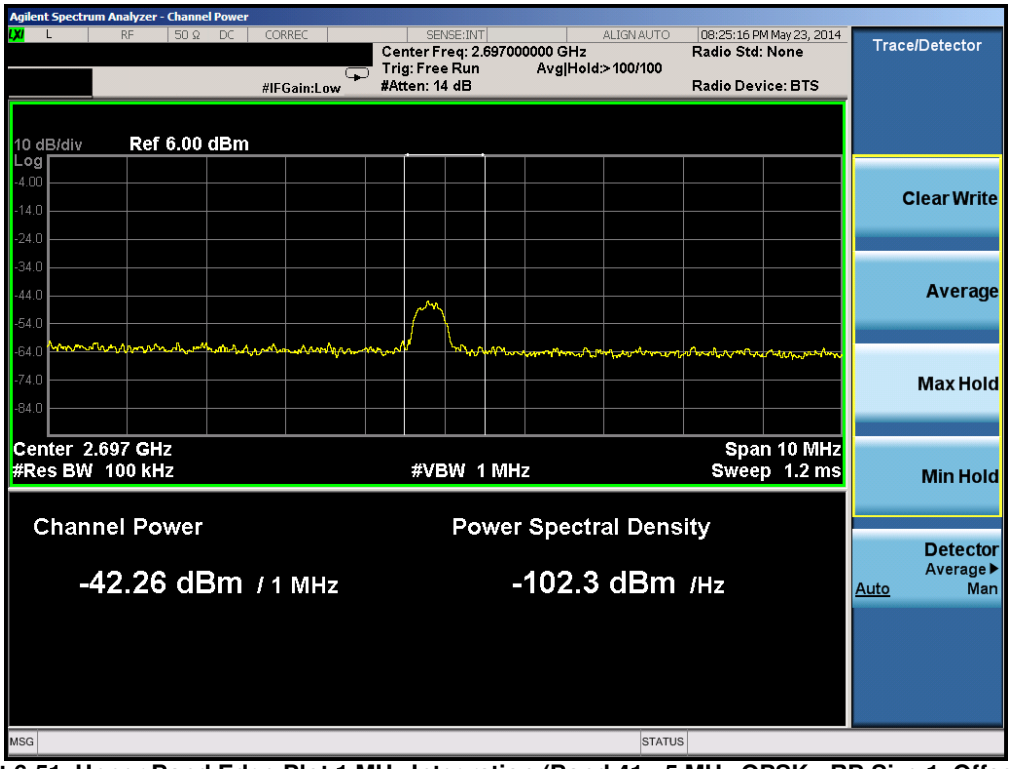
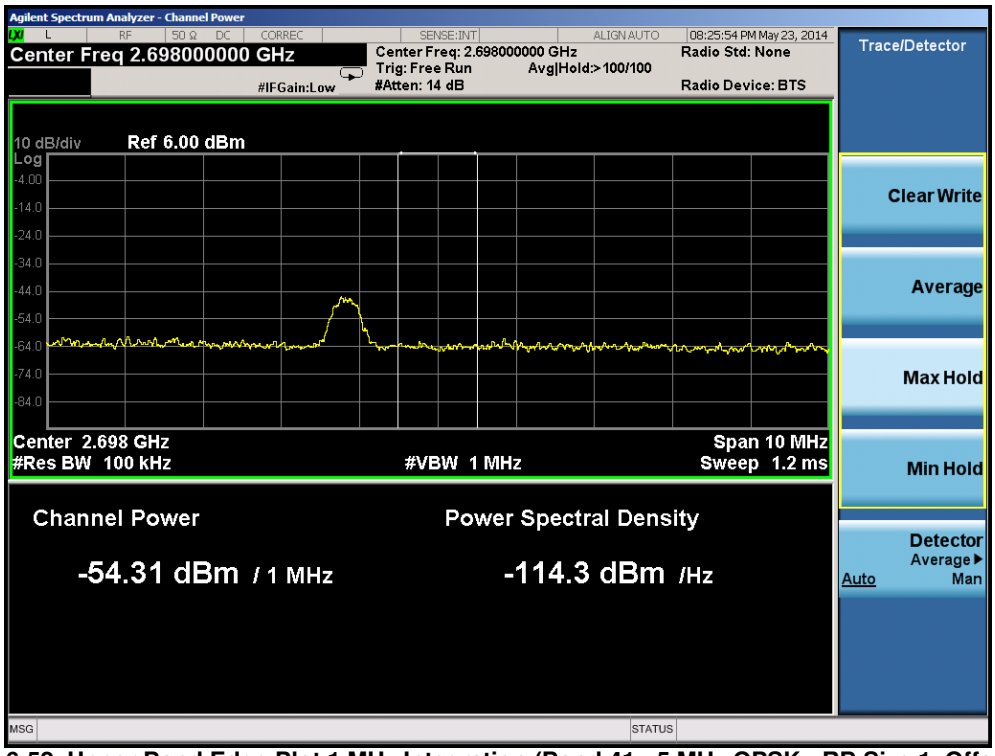


Plot 6-51. Upper Band Edge Plot 1 MHz Integration (Band 41 - 5 MHz QPSK - RB Size 1, Offset 0)



Plot 6-52. Upper Band Edge Plot 1 MHz Integration (Band 41 - 5 MHz QPSK - RB Size 1, Offset 0)

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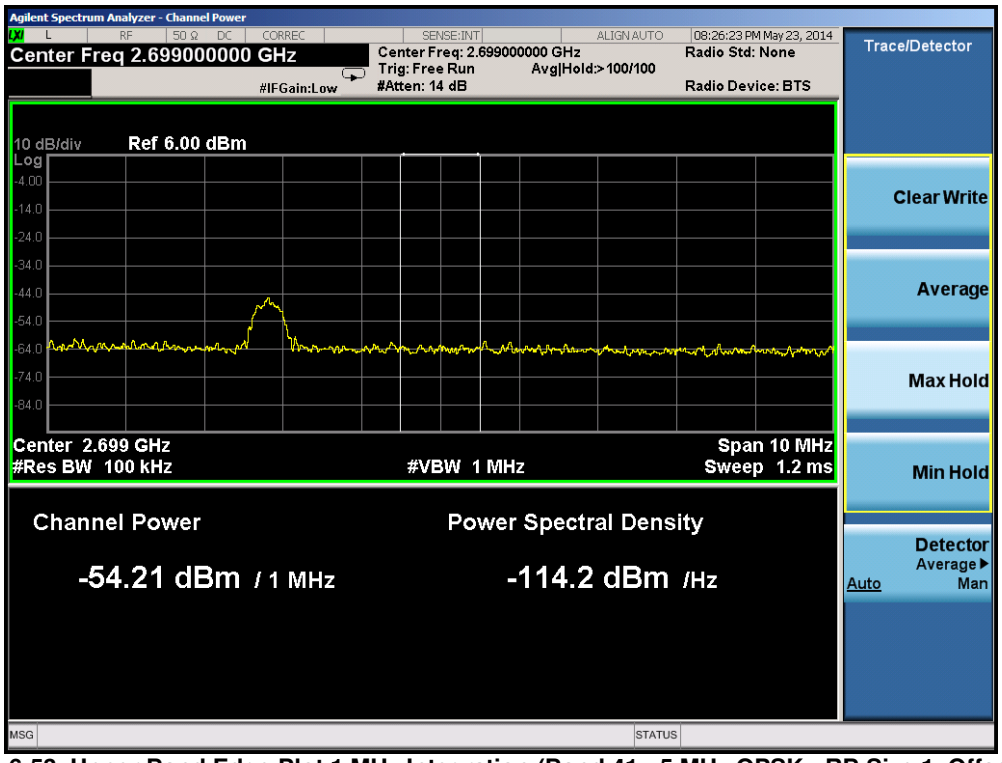
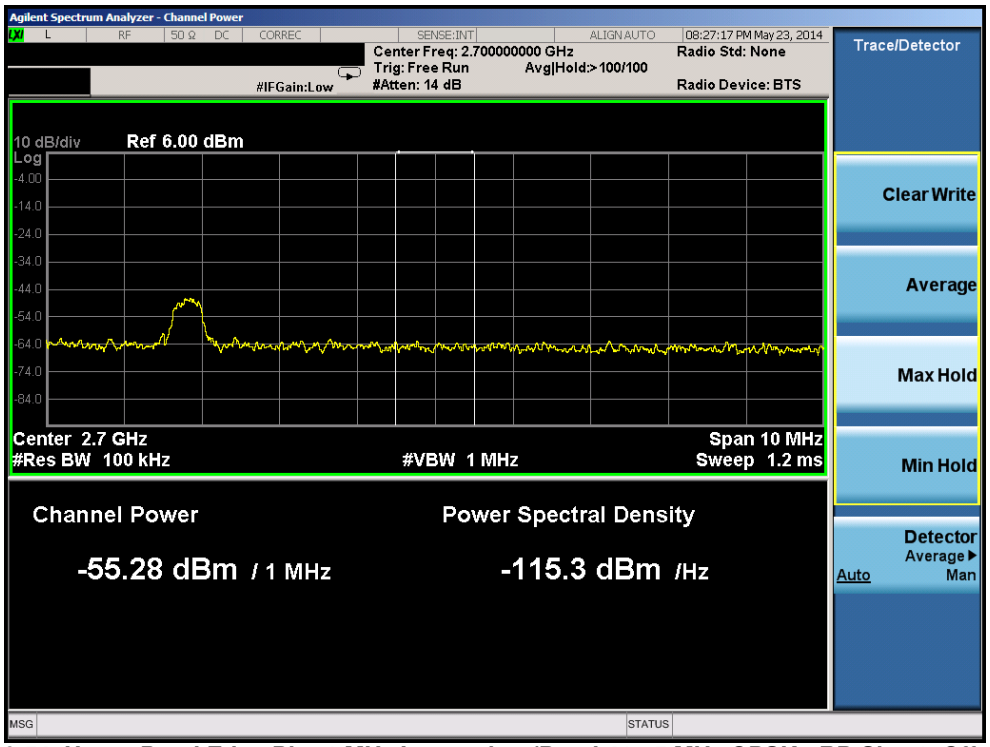


Plot 6-53. Upper Band Edge Plot 1 MHz Integration (Band 41 - 5 MHz QPSK - RB Size 1, Offset 0)



Plot 6-54. Upper Band Edge Plot 1 MHz Integration (Band 41 - 5 MHz QPSK - RB Size 1, Offset 0)

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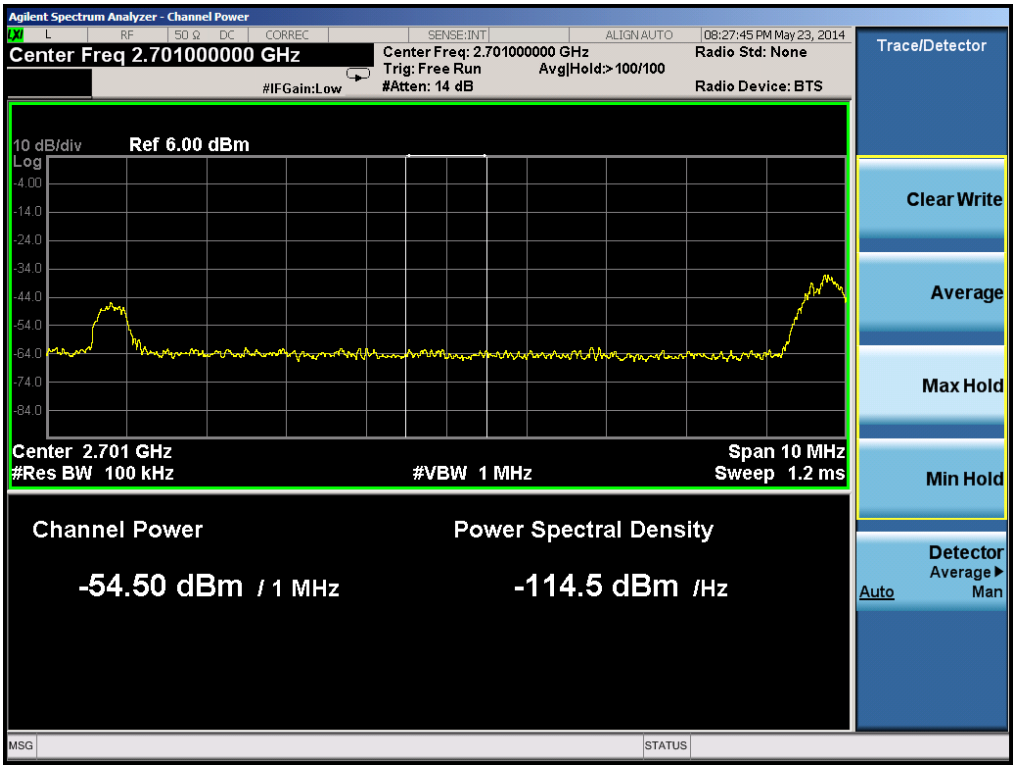
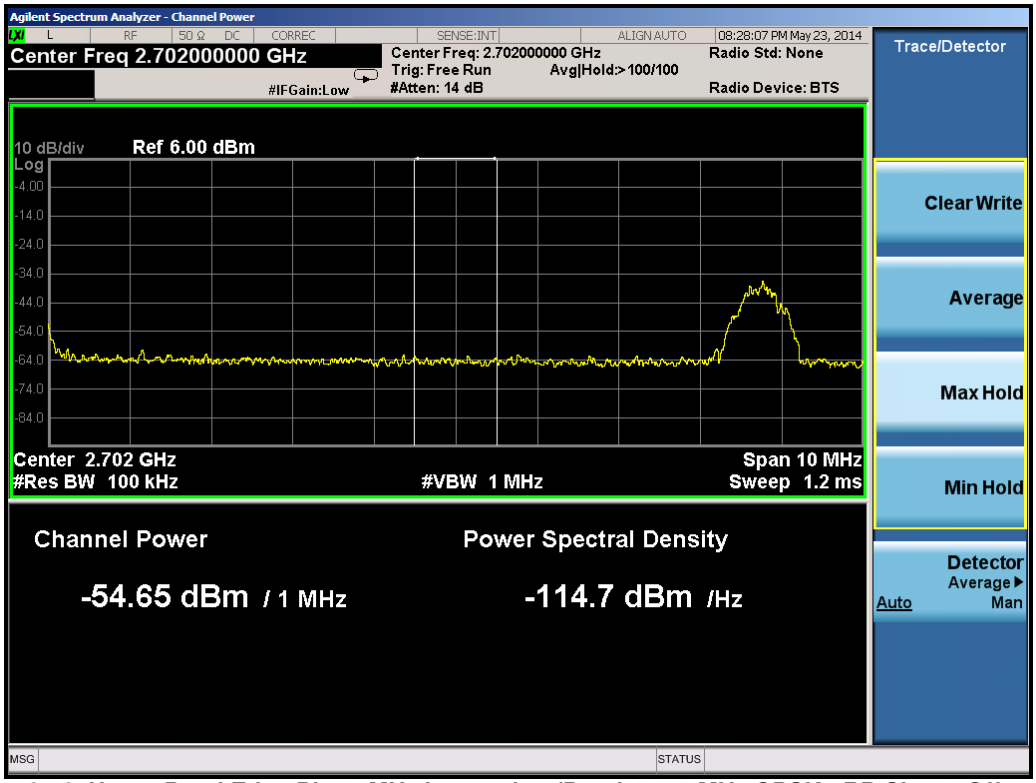


Plot 6-55. Upper Band Edge Plot 1 MHz Integration (Band 41 - 5 MHz QPSK - RB Size 1, Offset 0)



Plot 6-56. Upper Band Edge Plot 1 MHz Integration (Band 41 - 5 MHz QPSK - RB Size 1, Offset 0)

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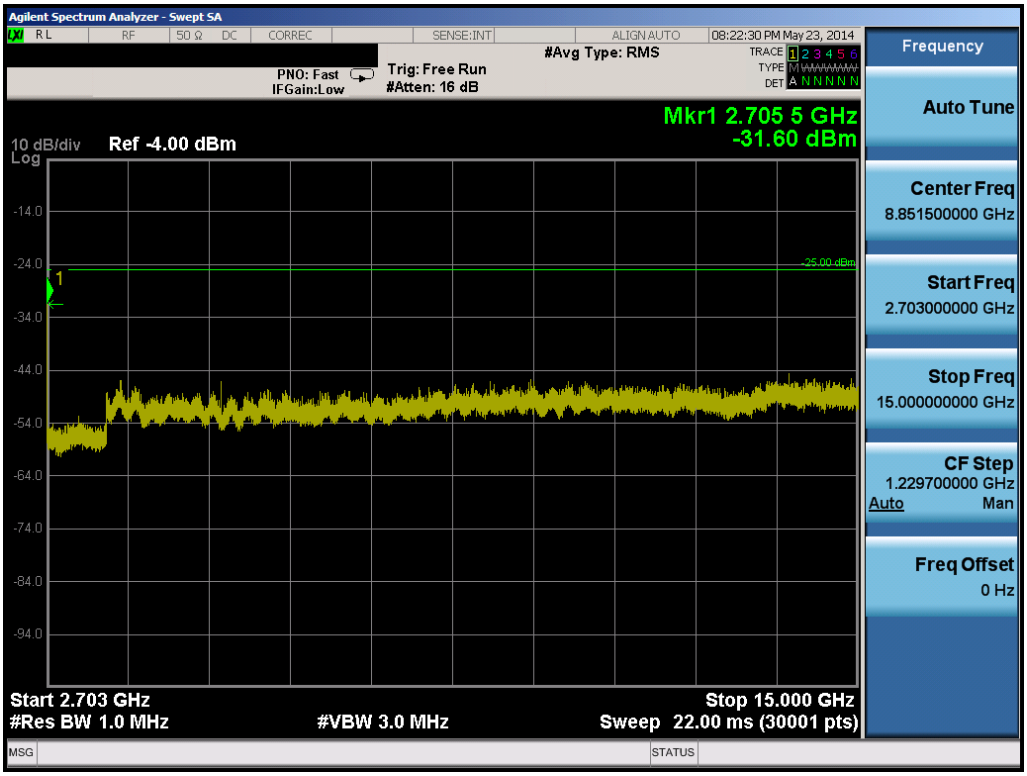
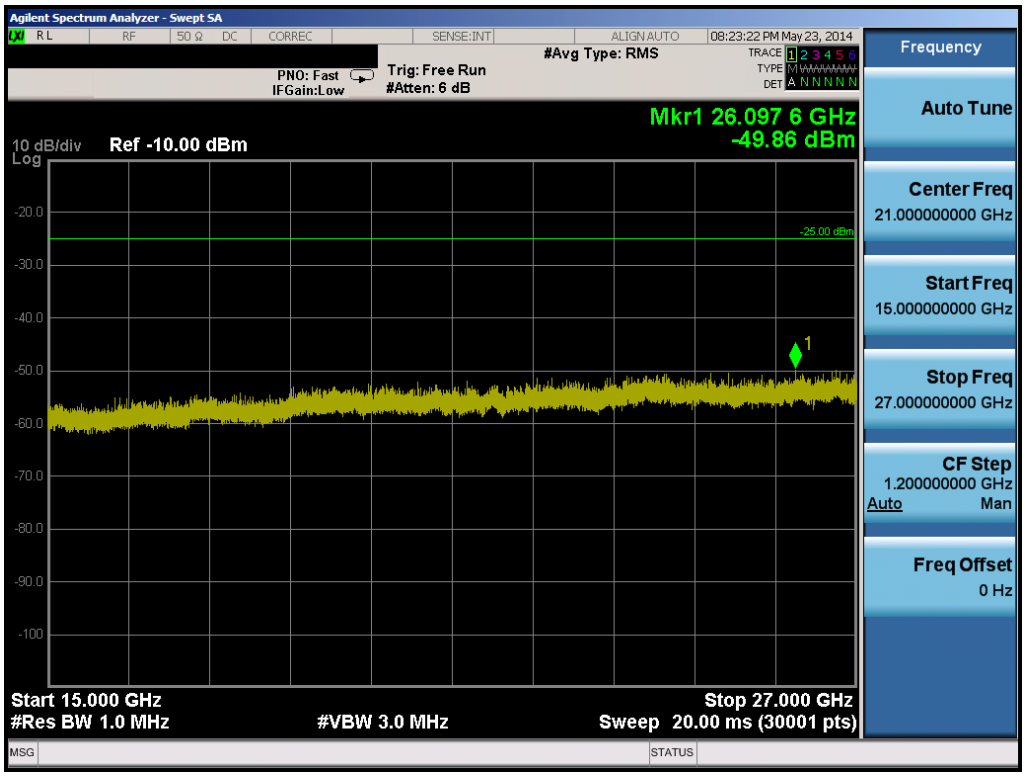


Plot 6-57. Conducted Spurious Plot (Band 41 – 5.0MHz QPSK – RB Size 1, RB Offset 0 – High Channel)



Plot 6-58. Conducted Spurious Plot (Band 41 – 5.0MHz QPSK – RB Size 1, RB Offset 0 – High Channel)

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